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DAAB07-78-C-2958

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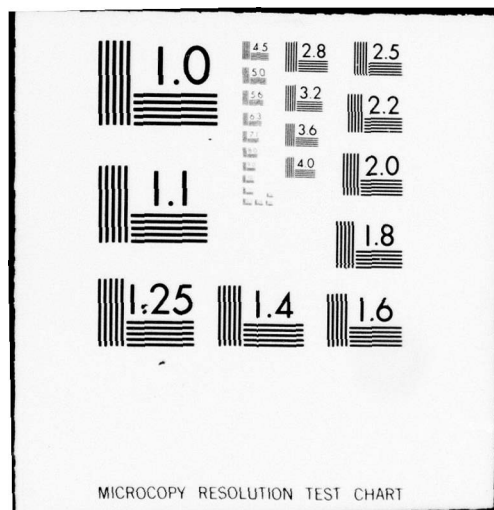
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Research and Development Technical Report
DELET-TR-78-2958-2

LOW NOISE EBS JAMMER

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June 1979

Second Triannual Report for Period 1 Dec 1978 - 31 Mar 1979

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Prepared for:
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US ARMY ELECTRONICS RESEARCH AND DEVELOPMENT COMMAND
FORT MONMOUTH, NEW JERSEY 07703

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LOW NOISE EBS JAMMER
SECOND TRIANNUAL REPORT
1 DECEMBER 1978 THROUGH 31 MARCH 1979

Contract No. DAAB 07-78-C-2958

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Prepared by:
Douglas B. Clark
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For
U.S. Army Electronics Technology & Devices Laboratory
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FOREWORD

Identification of Engineering Personnel

Douglas B. Clark, Project Engineer

John B. Rettig, Member of Technical Staff

Descriptive Background of Key Personnel

Biographical sketches for each of the key personnel are included in the Appendix.

Publication, Lectures, Reports and Conferences

- | | |
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| 1. Publications | None |
| 2. Lectures | None |
| 3. Reports | Monthly Status Reports
December 1978 through March 1979 |
| 4. Conferences | Progress on subject contract. Watkins-Johnson
Company personnel and Mr. Robert M. True of
ERADCOM, Fort Monmouth, N.J. Held at
Watkins-Johnson Company on 20-22 March 1979. |

Program for the Next Internal

The Program Plan shown in Figure 2-2 and described in Section 6.0 represents our best estimate of work to be carried out during the next reporting period.

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1.0 INTRODUCTION

1.1 Objective

The program objective is to reduce the output power level of spurious noise signals, intermodulation (IM) products and harmonic distortion generated by deflection modulated electron beam semiconductor (EBS) amplifiers.

1.2 Technical Approach

Figure 1-1 illustrates the configuration of a deflected beam EBS amplifier. This type of amplifier has been developed by Watkins-Johnson Company over a period of several years. Measurements of existing EBS amplifiers will be made to determine the typical values of IM products, spurious noise and harmonic distortion. The existing electron beam profile will be characterized using a slit beam analyzer. The EBS performance will be correlated to the measured beam profile using a mathematical analysis implemented by a computer program. A second computer program will perform an analysis of the expected beam profile generated by the existing gun geometry and these results will be correlated with the measured beam profile. Modifications will then be performed on the electron gun to improve the linearity, IM products and harmonic distortion; and the re-designed gun will be fabricated and tested on the beam analyzer. Two devices using the re-designed gun will be fabricated, tested and delivered as part of this contract.

DEFLECTED BEAM EBS

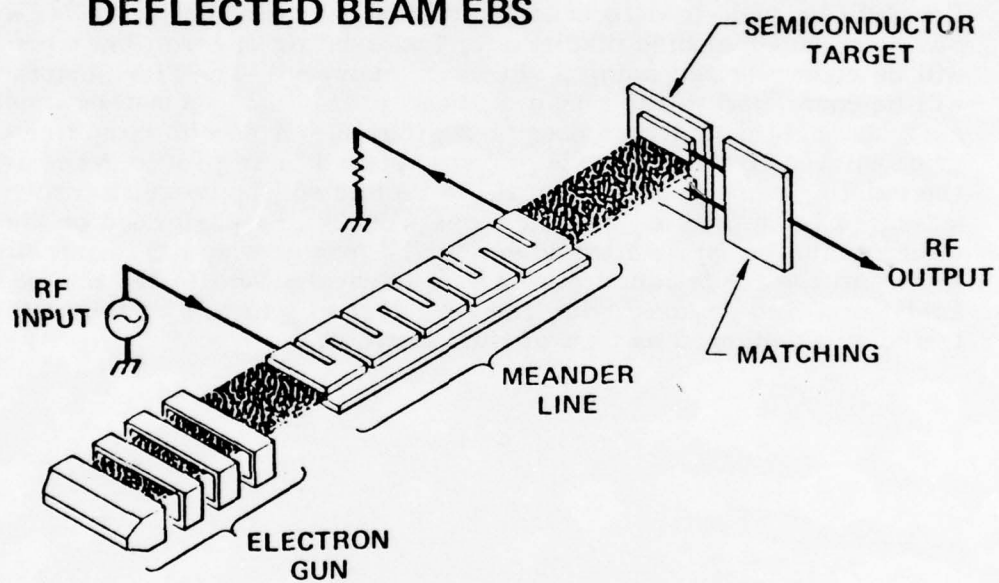


Figure 1-1. Deflected Beam EBS Configuration

2.0 PROGRAM SUMMARY

2.1 Summary of Work

During the four month period covered by this report, the following was accomplished:

1. The existing EBS amplifiers having 2×6 diode arrays were completely characterized in terms of linearity and intermodulation products as a function of device efficiency.
2. The computer aided analysis of the present gun performance was completed. Several conclusions were drawn from the results, and areas of potential improvements were identified.
3. Work continued on methods of analyzing actual shape of electron beams. Calibration of an existing slit diode array was not satisfactory, so a fabrication of a new slit diode array was begun. Phosphor screens were used as a secondary method of beamshape observation.
4. Several guns were checked using the phosphor screen method. Poor beam shape was observed, and the guns were checked for dimensional conformation to the present design. Some problems were identified in this regard, and redesigned tooling and parts were ordered to correct these problems.

2.2 Program Schedule

Figure 2-1 shows the Program Schedule, updated as of April 1979. The primary cause of slippage has been lack of a suitable method of measuring beam shape. This problem has been solved by the use of phosphor screens and the fabrication of a new slit diode array.

All other tasks are proceeding on schedule with one exception: because of results obtained by beam shape analysis performed as part of this program, emphasis has been shifted away from the development of the metal-ceramic version of the sheet beam gun and increased emphasis has been put on fabrication techniques using the present glass envelope configuration. For this reason, the two tasks having to do with development of the metal ceramic gun have been deleted from the program.

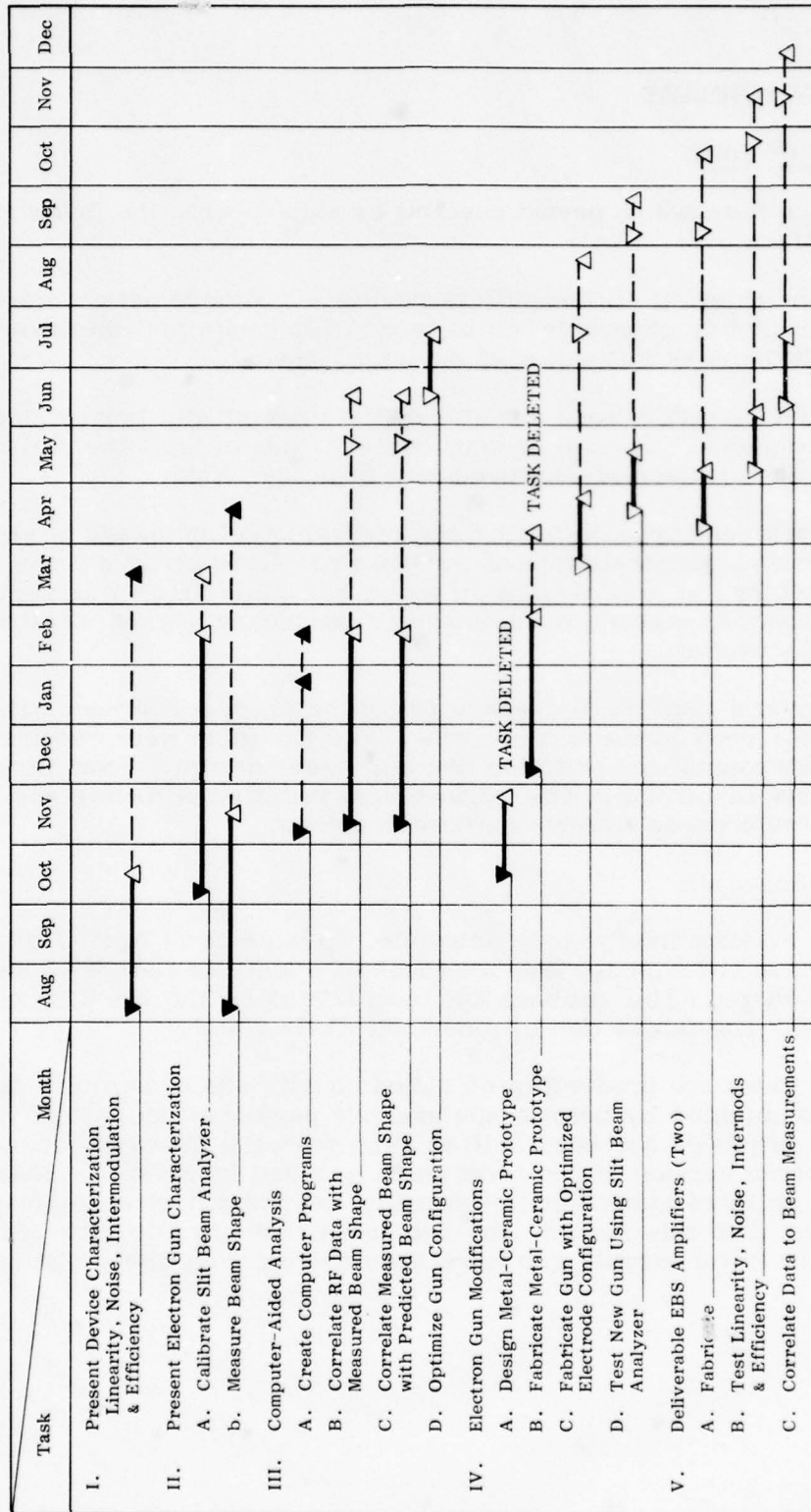


Figure 2-1. Program Milestone Schedule

3.0 CHARACTERIZATION OF EXISTING DEVICES

Extensive linearity and intermodulation measurements were performed on a deflected beam amplifier, WJ-3662-1 S/N 9. The device was set up for saturated output power of 46.0 dBm at maximum efficiency. The balanced two tone method of measurement was used, and in most cases, the fundamental tones and their 3rd, 5th, and 7th intermodulation products were measured over a 20-33 dB dynamic range. The parameter varied during these tests was the voltage on anode 3, the next to last anode in the gun stack. (Anode 4 is held at ground potential.) Figures 3-1 through 3-5 summarize these results, and Figure 3-6 expresses the tradeoff between linearity and efficiency. The criterion for linearity is the maximum 3rd order intermodulation product referenced to fundamental saturation level; note that the case for "best" linearity by this criterion ($A_3 = 3400$) is not coincident with the case where the fundamental deviates the least from constant gain ($A_3 = 3500$), nor with the case where single tone saturated efficiency is maximum ($A_3 = 3300$). The reason for this is attributed to the sidelobes present in the beam density profile, which has been observed on phosphor screens. At maximum efficiency, the amplifier is running in class C, i.e., with a tightly focused beam smaller than the diode spacing. At other points, class AB predominates, with current spillover severely reducing efficiency. Since the beam profile as predicted by computer for class C is not perfectly rectangular, the intermodulation products are more severe than for class AB, which in spite of spillover has a better beamshape within the width of the diode spacing.

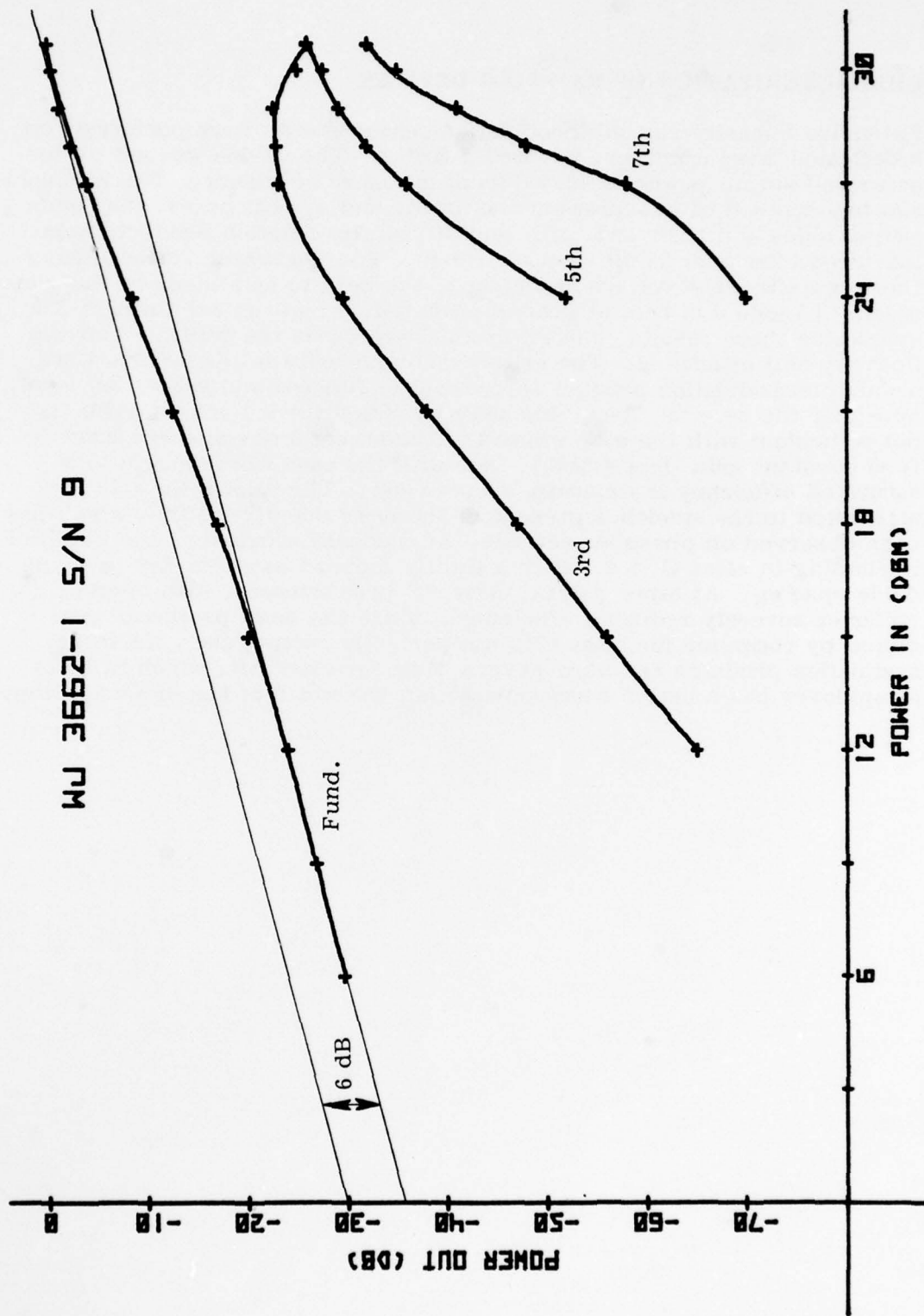


Figure 3-1. IMD Performance ($A_3 = 3100$ V).

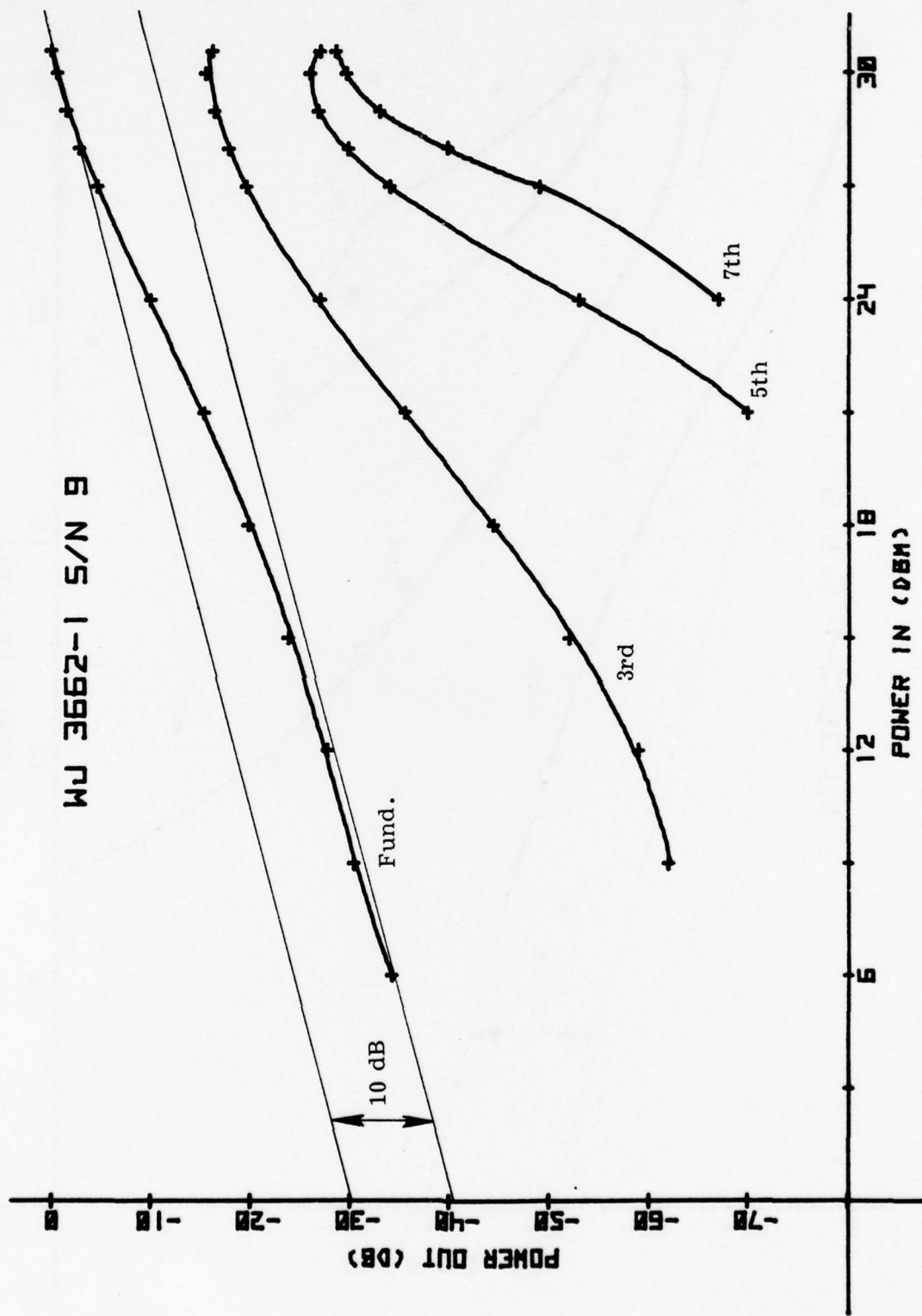


Figure 3-2. IMD Performance ($A_3 = 3200$ V).

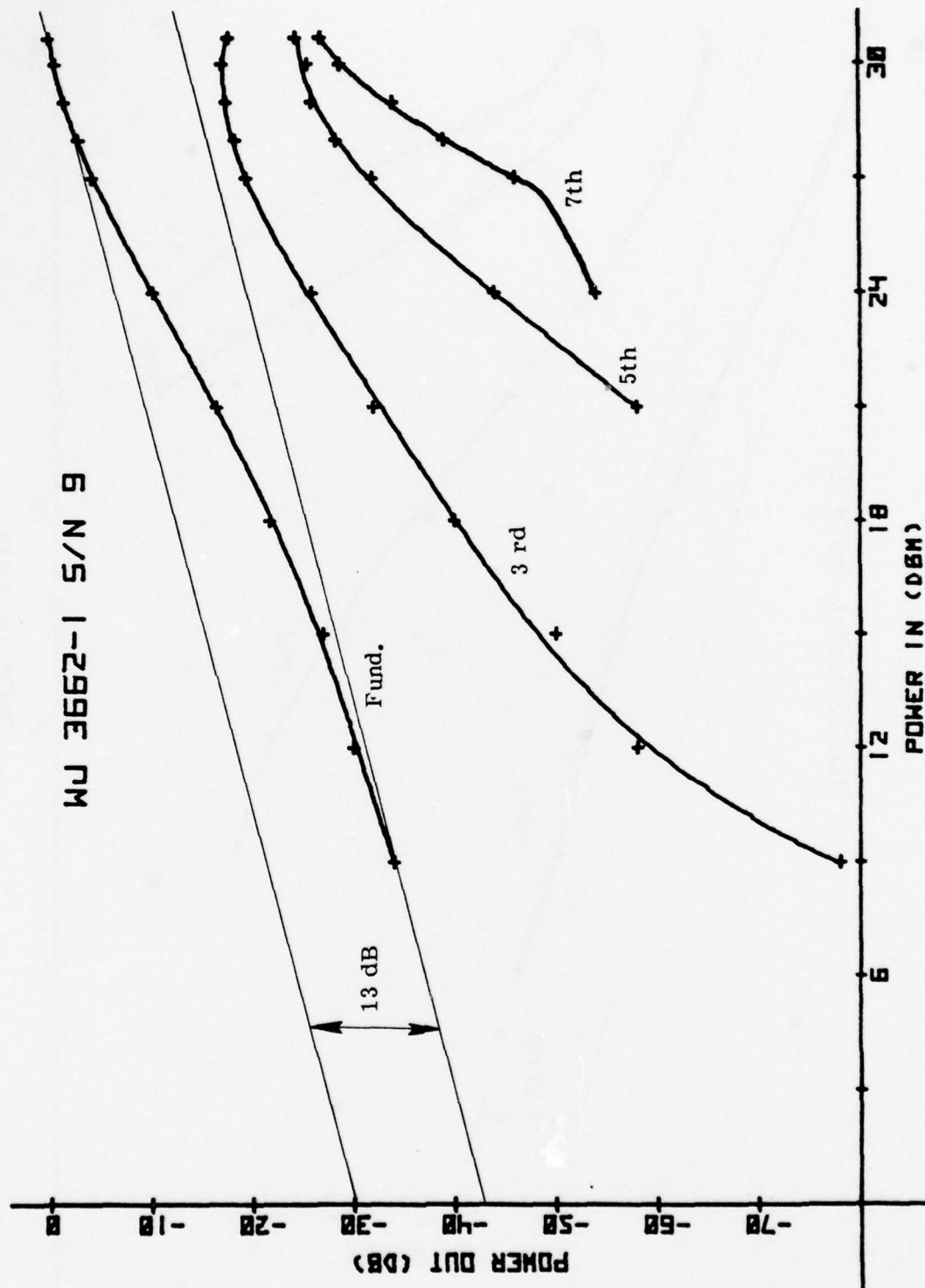


Figure 3-3. IMD Performance for the Case Where Maximum Target Efficiency Is Attained at Single Tone Saturation ($A_3 = 3300$ V).

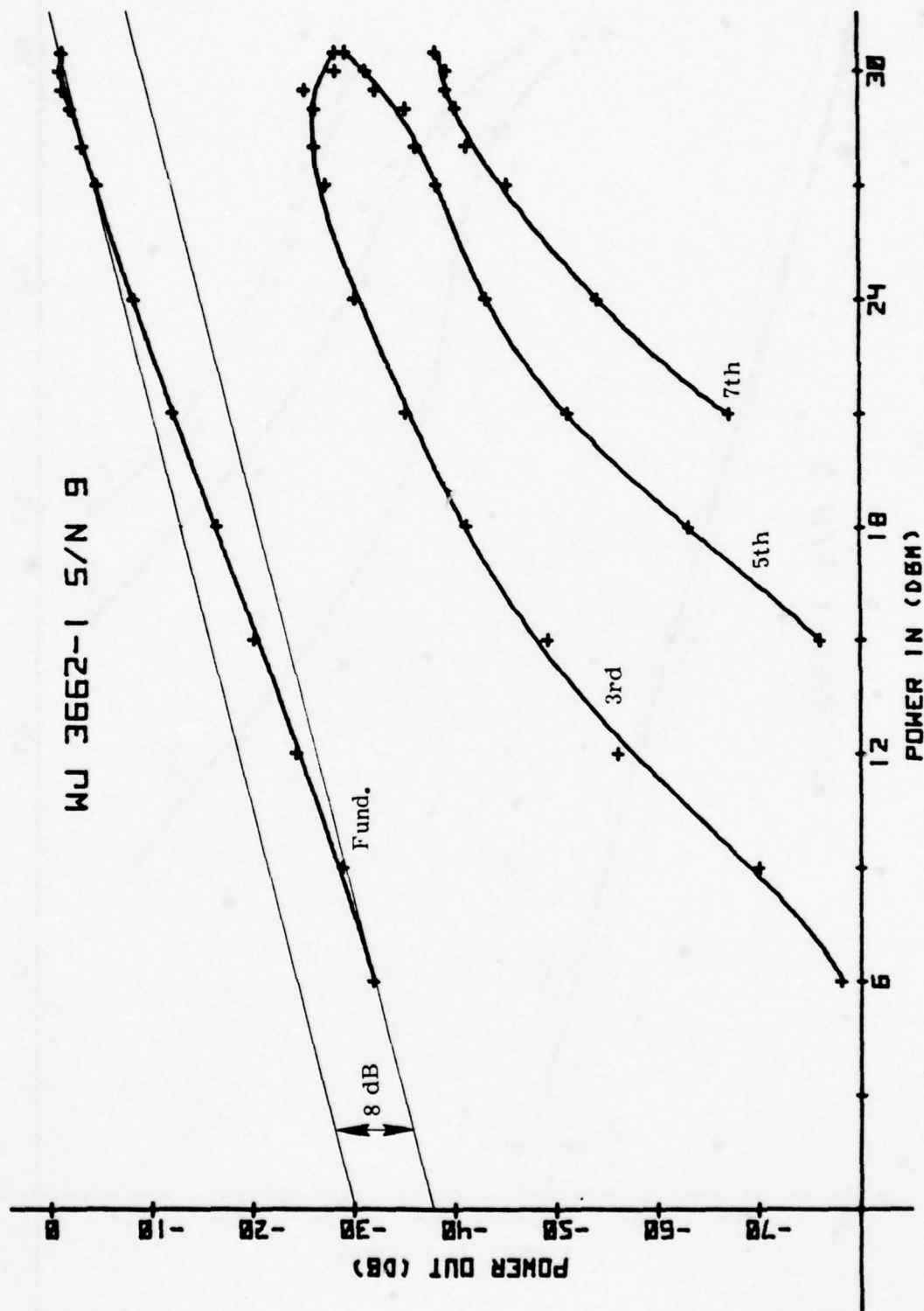


Figure 3-4. IMD Performance for the Case where Maximum 3rd Order IMD Is Minimized ($A_3 = 3400$ V).

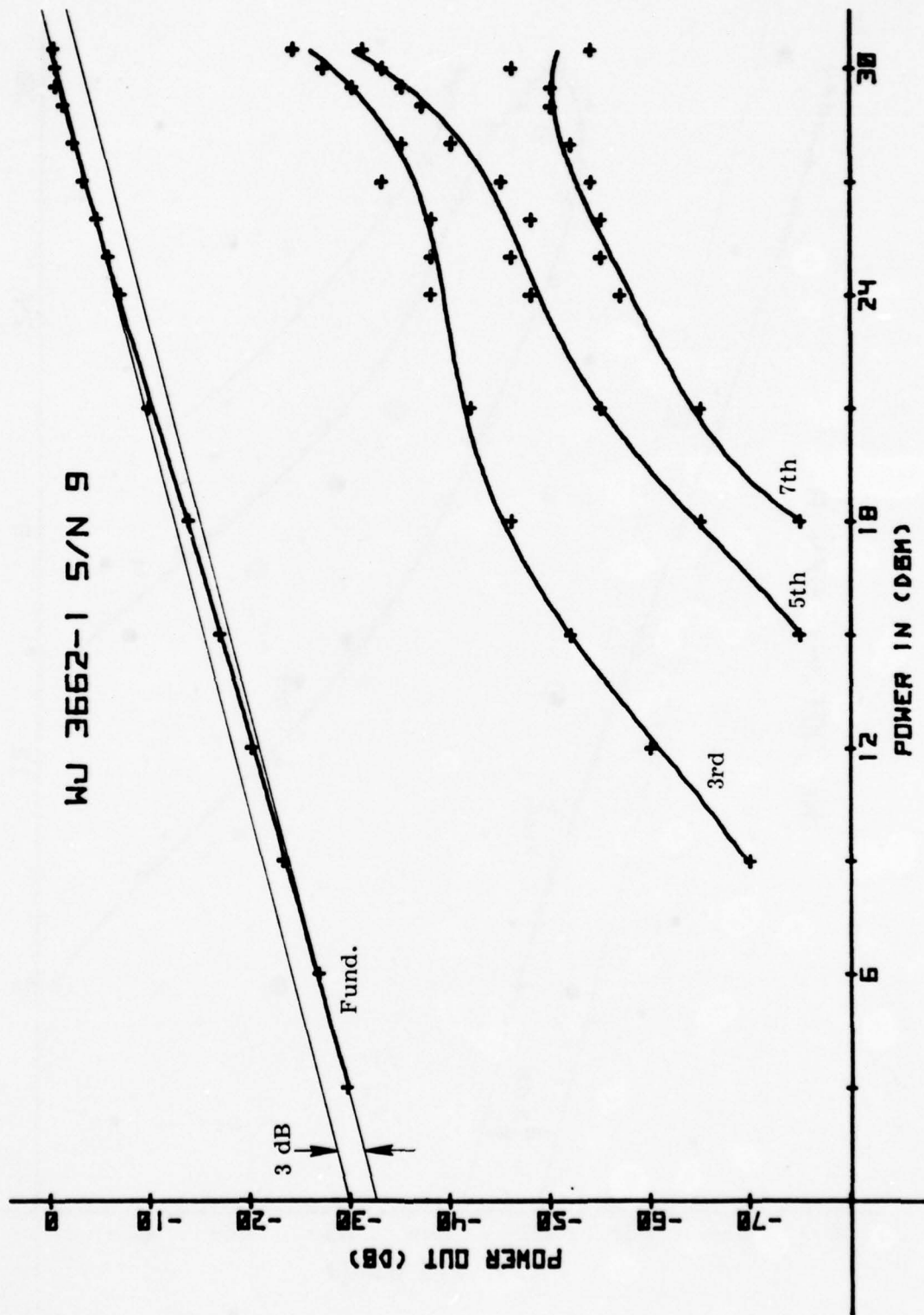


Figure 3-5. IMD Performance ($A_3 = 3500$ V).

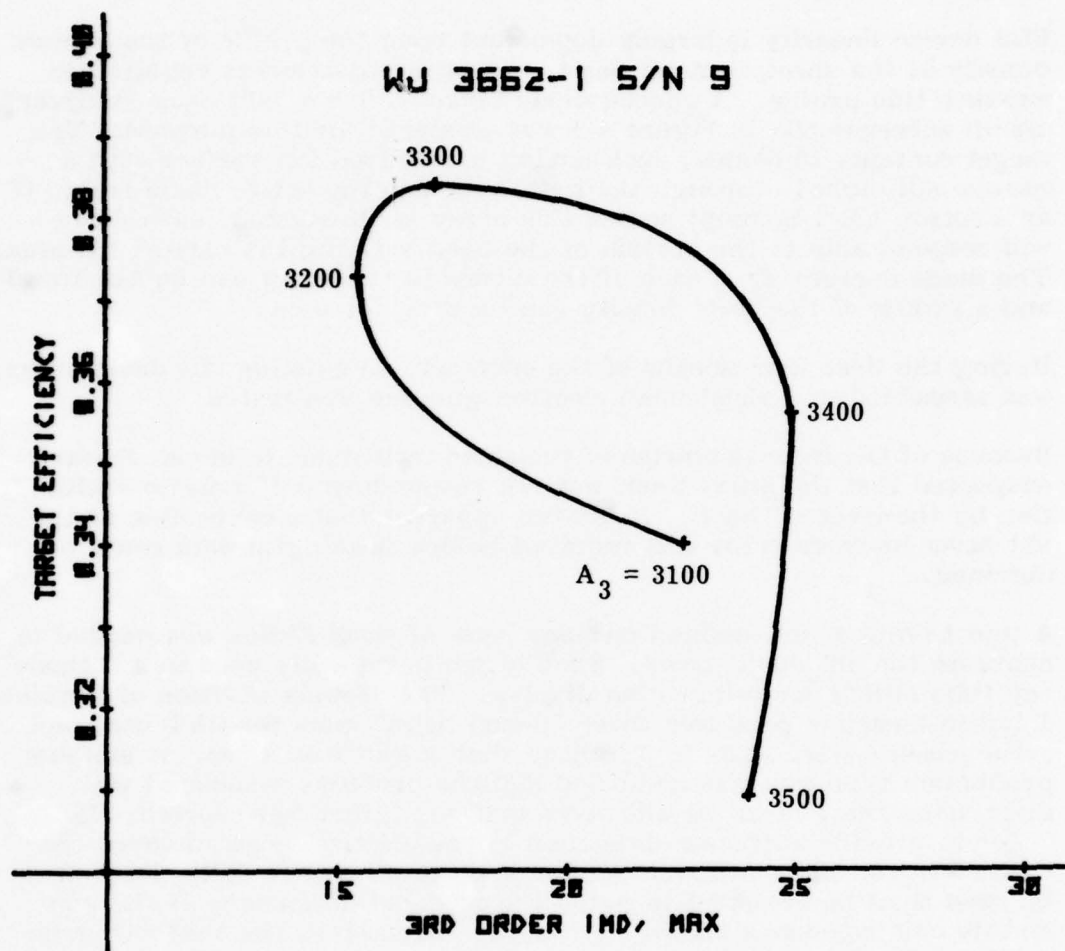


Figure 3-6. Linearity/Efficiency Tradeoff, expressed parametrically as a function of Anode 3 voltage.

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4.0 MEASUREMENT OF ELECTRON BEAM SHAPE

4.1 Slit Diode Array

EBS device linearity is largely dependent upon the profile of the current density of the sheet electron beam. An accurate means is required to measure this profile. A special diode target called a "slit beam analyzer" shown schematically in Figure 4-1 was prepared for this purpose. The target contains 10 diodes, each having a metalized top surface with a narrow slit etched through the metalization to the active diode layer. If an electron beam is swept across this array as illustrated, each diode will respond only to the portion of the beam striking the narrow slit area. The diode current from each of the diodes in the array can be monitored and a profile of the beam density can be thus obtained.

During the first four months of the contract, an existing slit diode array was assembled to a sheet beam electron gun and was tested.

Because of the inconsistencies of response from diode to diode, it was suspected that the array itself was not responding uniformly to excitation by the electron beam. It became apparent that a calibration of the slit beam analyzer array was required before meaningful data could be obtained.

A gun having a well-defined circular beam of small radius was needed to calibrate the slit diode array. Such a gun is typically used in a cathode ray tube (CRT) for information display. The Stewart Division of Watkins-Johnson Company produces these "pencil beam" guns for CRT use, and arrangements were made to purchase such a gun from them. A suitable production type gun was identified and the problems associated with interfacing the gun to the slit beam analyzer target were solved. In order to provide sufficient deflection of the electron beam to cover the entire target, using available sawtooth generators, the deflection coil to be used must be designed to match the physical dimensions of the gun and its coil impedance should be roughly the same as the sawtooth generator output impedance. A suitable coil was designed and procured from an outside vendor.

When the pencil beam gun was operated with the slit diode array, the diode current obtained was insufficient to provide a high enough signal-to-noise ratio. In addition, problems were experienced in obtaining a reasonable amount of cathode current from the gun.

The gun was removed from the slit diode array and sent back to the Stewart Division for installation of a new cathode. In conjunction with

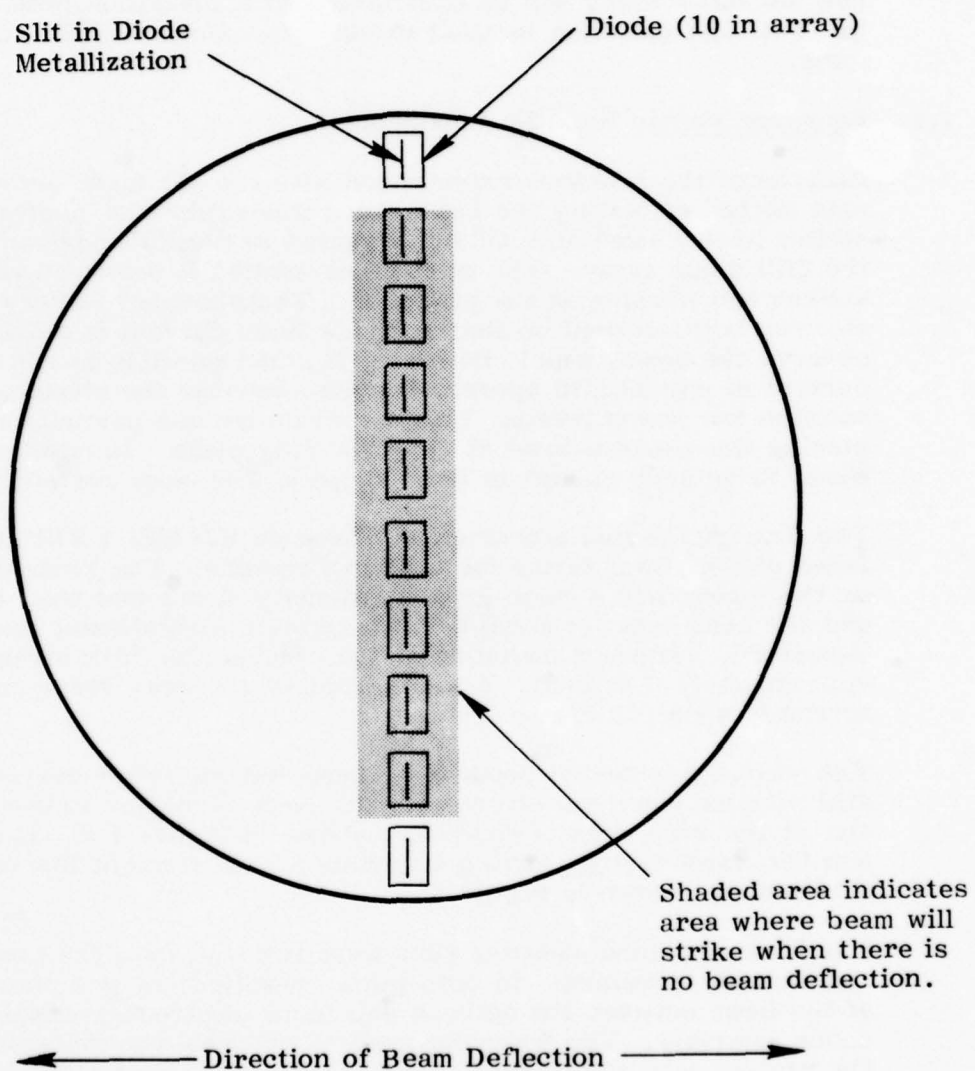


Figure 4-1. Slit Beam Analyzer Array

this, fabrication of a new slit diode array was begun, since several of the diodes in the slit diode array were not functioning.

The new slit diode array will have wider (0.002 inches) slits to provide greater response amplitude. Since the optimum beam width is 0.040 inches, resolution will still be far in excess of what is required. The new slit diode array will be first tested with the pencil beam gun to calibrate it, and can then be used to test beam shape on EBS sheet beam guns.

4.2 Phosphor Screen Beam Measurements

Because of the problems experienced with the slit diode array, an alternate method of testing the beam shape was explored. A phosphor screen similar to that used on a CRT is mounted to the EBS device in place of the EBS diode array. The beam cross-section is observed when the beam strikes and illuminates the phosphor. The phosphor is very sensitive to electron bombardment so that very low beam current is sufficient to observe the beam shape. However, it is not possible to run high beam current at normal EBS operating levels, because the phosphor is evaporated at low power levels. This disadvantage was partially alleviated by pulsing the electron beam at very low duty cycle. In addition, there seems to be little change in beam shape as the beam current is increased.

The first gun tested was originally used on WJ-3662-1 S/N 16, which failed at low power levels for unknown reasons. The beam shape shown on the screen had a much greater intensity at one end than at the other, and the beam was not straight but exhibited a significant amount of curvature. Maximum deviation of the beam center from straight line was approximately 0.04 inch. A photograph of the beam image on the phosphor screen is shown in Figure 4-2.

The second gun tested produced a beam having better overall shape, but still with too much curvature and with some increase in intensity and beam size at the very ends of the beam, shown in Figure 4-3. The third gun was the worst tested, having a deviation from straight line of approximately 0.05 inches, shown in Figure 4-4.

The first and third electron guns were removed from the phosphor screens and visually examined. In both guns, misalignment was noted in the plane of the beam between the cathode and focus electrode assembly and the anode assembly. The fixturing used to assemble the guns was checked and the problem was apparent - when the lengthwise dimension of the focus electrode assembly was increased in early 1978, the fixture had not been modified to take up the slack. New fixturing to correct the problem was ordered.

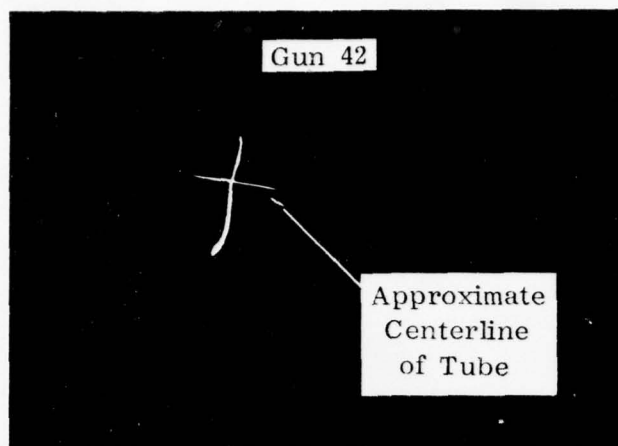


Figure 4.2 - Beam shape of gun #42 measured on a phosphor screen

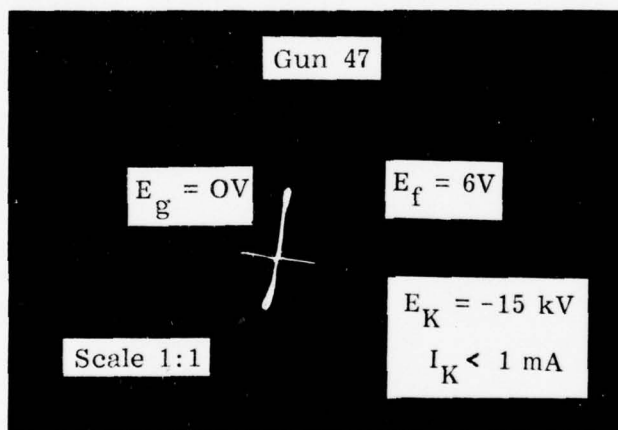


Figure 4.3 - Beam shape of gun #47 measured on phosphor screen.

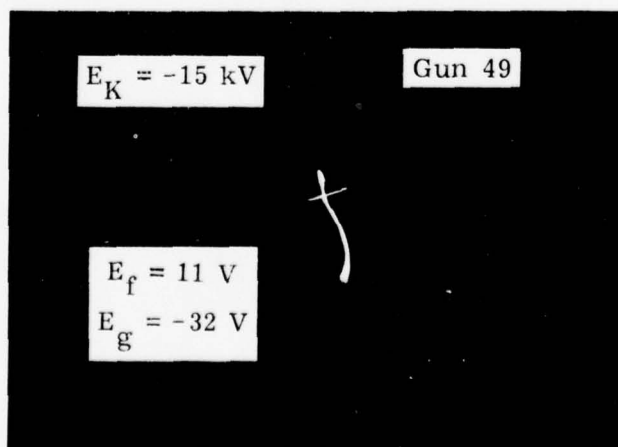


Figure 4.4 - Beam shape of gun #49 measured on a phosphor screen.

The last gun, which had the most pronounced beam curvature, also had a noticeable warpage in the first anode.

To reduce the "dogbone" effect of higher beam size and intensity near the ends of the beams, modifications were begun on the gun electrode designs. The modifications will increase the length of the slot in all the gun electrodes.

To increase the precision of the anodes themselves, a new method of fabricating the anodes was developed. Presently, each anode is machined to the desired dimensions. The new method involves machining each anode in two parts, placing the parts on a mandrel, and laser welding the two pieces together. Since the mandrel can be made with very good accuracy, the internal dimensions of the finished anode should be better using the new method.

5.0 COMPUTER AIDED ANALYSIS OF ELECTRON GUN

During the present reporting period, the final computer program was written to complete the correlation between the rectangular gun geometry and the Fourier components of the output signal. All of the programs currently used for gun analysis are listed in Table I. The first three perform the function of determining beam profile through the acceleration region, i.e., up to the meanderline. The fourth accounts for beams spread through the drift region, from the meanderline to the target. Finally, the last performs a convolution of the beam density profile with diode shape to determine the output waveform, then does a Fourier transform on this waveform to determine the spectral components and calculates the target efficiency for the fundamental.

The design of a new gun structure has typically involved the use of only the first two programs. Generally, the quality of the beamshape is quite obvious after the second program is run, and if there are severe problems with a design, there is no point in carrying out further calculations. For this reason, Parts (1) and (2) of Table I have been streamlined to run with one job submission. The remainder of the programs, however, take a great deal of effort to run, and are used only to check out a design that has been finalized from (2). A complete listing of all above programs is given in Appendices I through IV.

Table I

COMPUTER ELECTRON OPTICS PROGRAMS
AVAILABLE FOR GUN ANALYSIS

<u>Name</u>	<u>System</u>	<u>Language</u>	<u>Purpose</u>	<u>Author</u>	<u>Listing</u>
1. RCTGUN I	IBM VM370	FORTRAN	Equipotential locator to set up RCTGUN II	John Rettig	Appendix I
2. RCTGUN II (XMGUN)	IBM VM370	FORTRAN	Slow region beam analysis	George Wada	(Proprietary)
3. RCTGUN III	IBM VM370	FORTRAN	Fast region, large area beam analysis	John Rettig	Appendix II
4. Beamspread	HP 9825A	HPL	Beamspread through drift space	John Rettig	Appendix III
5. Convolve	HP 9825A	HPL	Beam density convolution, and FFT analysis of output waveform and efficiency calculation	Steve Brierley	Appendix IV

6.0 MODIFICATION TO ELECTRON GUN

Figure 6-1 and 6-2 illustrate the 2-dimensional beam profile resulting from the present electrode geometry and ideal Pierce geometry, respectively. Figure 6-2 has served as a model for the development of a new anode geometry, based on the following areas of improvement that have been identified from Figure 6-1:

1. The effective cathode location is not necessarily at the zero potential line.
2. The grid is biased negative relative to the cathode, in order to reduce emission. As mentioned previously, this crowds the emission density into the center of the cathode.
3. Potentials farther from the cathode are such that emission at the cathode can not be reduced without causing the beam area to be smaller, thereby increasing current density.

Problems (2) and (3) are being addressed by construction of a gridded anode in front of the cathode, which will take over the function of beam control and allow the focus anode to be run at or near cathode potential. Problem (1) is not being pursued at this time because the flexibility of the new geometry should allow small adjustments to be made on the focus anode potential, in order to satisfy the Pierce field characteristics. Note that the intent of the gridded anode is to shield the Pierce field region from the acceleration region of the gun, to prevent the lensing effects seen in Figure 6-1. The beam control function is a necessary side effect of the primary shielding function, and is predicted to require potentials of 100-200 volts relative to cathode.

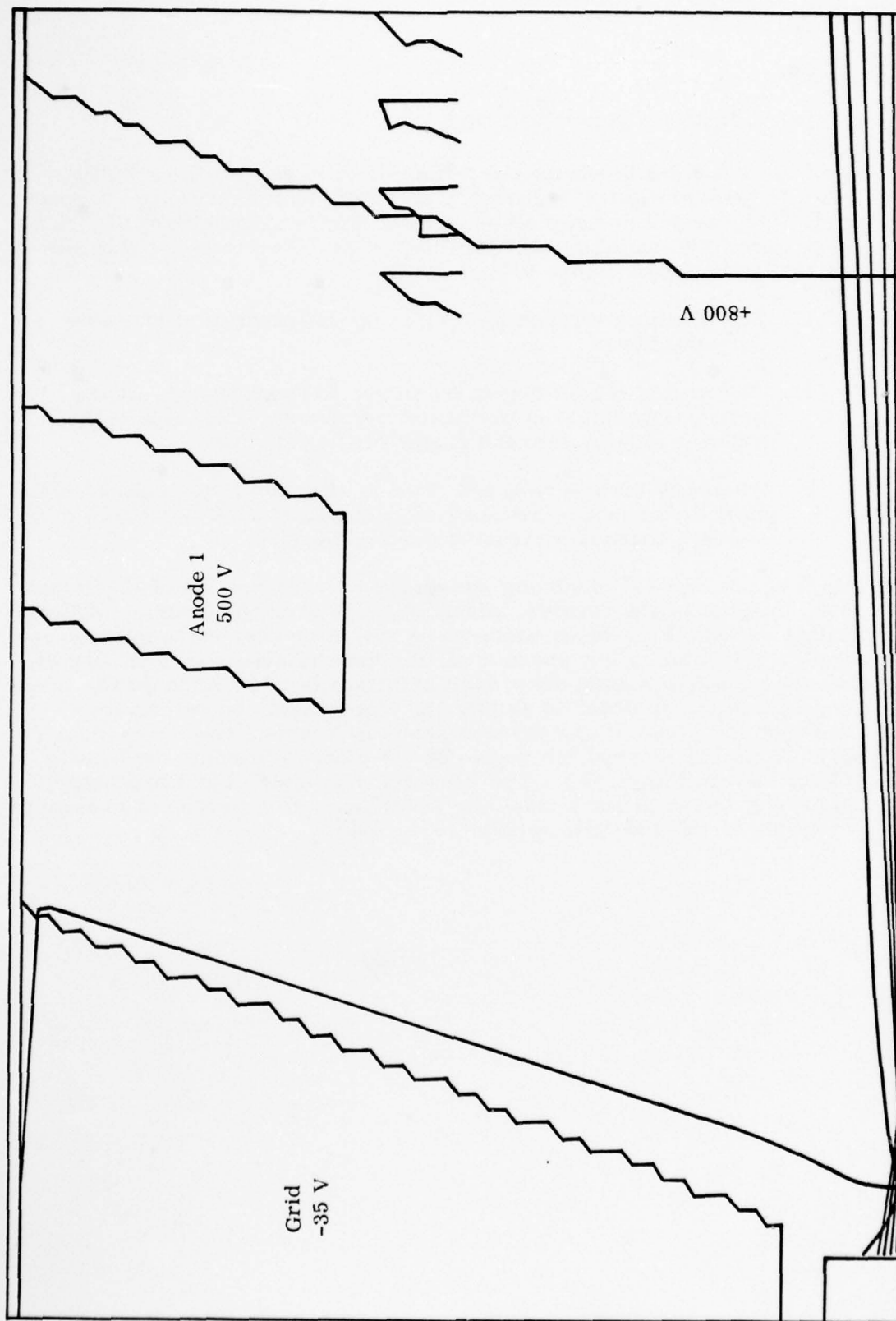


Figure 6-1. Part of the trajectory solution for the rectangular beam gun used in the 3662 Amplifier.

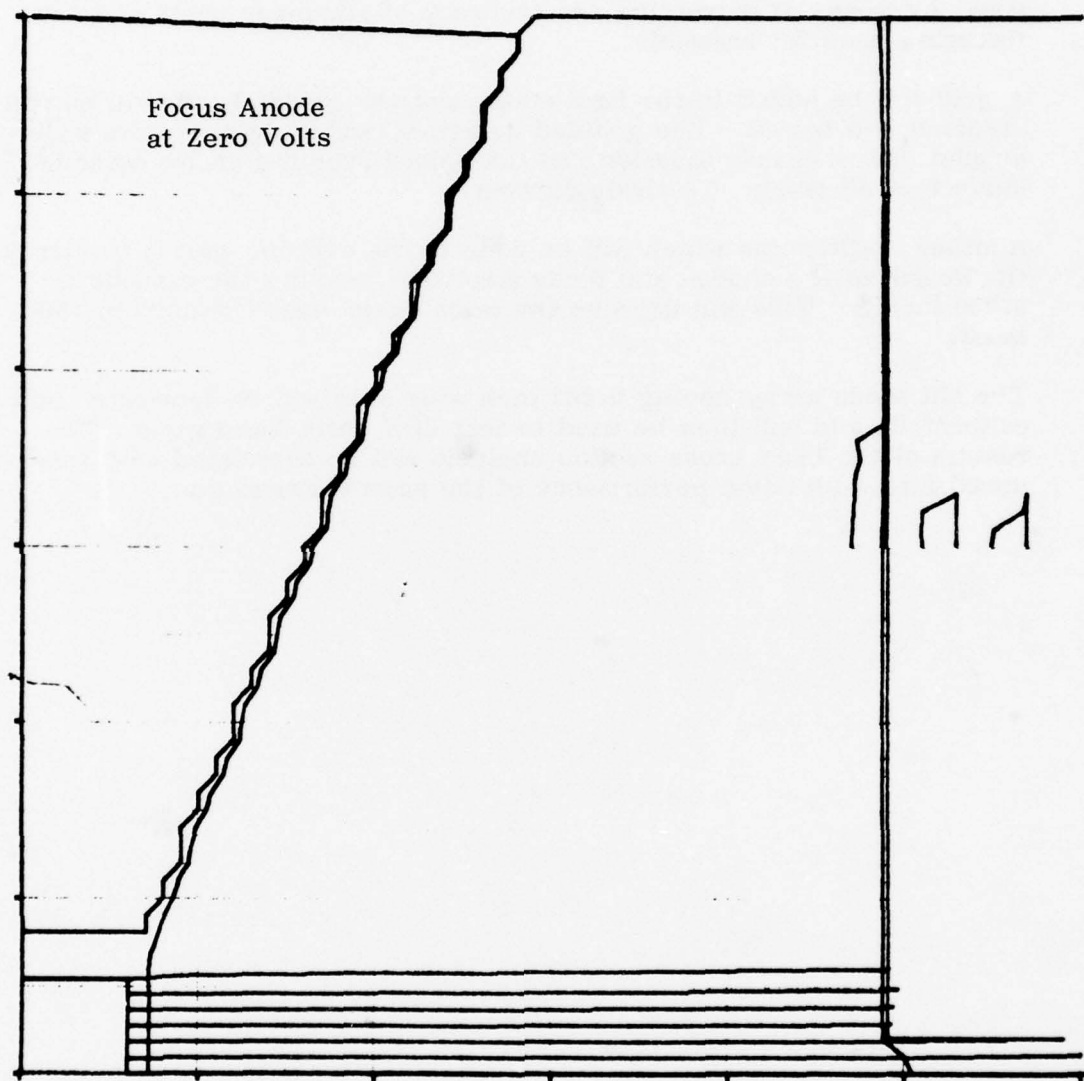


Figure 6-2. The Pierce Geometry Necessary to Draw a Uniform Beam Off the Cathode

7.0 PROGRAM FOR THE NEXT PERIOD

During the next four month period, effort will be directed at developing a method of producing electron guns with improved cross-sectional profiles, by means of increasing the accuracy of the piece parts and the fixturing used for assembly.

A grid will be added to the first anode and the gridded gun will be constructed and tested. The gridded design should provide a more well-shaped beam because emission can take place over the entire cathode surface at all levels of cathode current.

Another modification which will be done to the existing gun is to increase the length of the anodes and focus electrode, leaving the cathode at 0.700 inches. This will improve the beam shape near the ends of the beam.

The slit diode array having 0.002 inch wide slits will be fabricated and calibrated, and will then be used to test EBS sheet beam guns. The results of the beam cross-section analysis will be correlated with measured intermodulation performance of the same electron gun.

Appendix I

RCTGUN I

C		GUN00010
C	GUN00020
C		GUN00030
C		GUN00040
C	RECTANGULAR GUN ANALYSIS PACKAGE	GUN00050
C		GUN00060
C	JOHN B RETTIG 1/31/79	GUN00070
C		GUN00080
C		GUN00090
C	MAIN DRIVER ROUTINE, PART I - EQUIPOTENTIAL SOLUTIONS	GUN00100
	IMPLICIT REAL*8 (A-H,O-Z)	GUN00110
	REAL*8 V(41,401)	GUN00120
	REAL*8 COND(9)	GUN00130
	REAL*8 X(200),Y(200),UX(200),UY(200)	GUN00140
	REAL*8 TITLE(4)	GUN00150
	INTEGER ICOND(9)	GUN00160
	COMMON /A/ V	GUN00170
	COMMON /B/ XMIN,XMAX,DXO,	GUN00180
	* YMIN,YMAX,DYO,	GUN00190
	* M,N,NXY	GUN00200
	COMMON /C/ COND,ICOND,NCOND,CMIN,CMAX,COFF	GUN00210
	COMMON /D/ X,Y,UX,UY	GUN00220
	COMMON /E/ TITLE	GUN00230
	DATA BW /.2/	GUN00240
	DATA NEQP /31/	GUN00250
	DATA YEQP /4.5D-3/	GUN00260
	DATA RELERR /1.D-4/	GUN00270
	DATA ITER /20/	GUN00280
	DATA X1,X2,Y1,Y2 /0.,4.D-3,0.,6.D-3/	GUN00290
	DATA ENGMET /39.37/	GUN00300
C		GUN00310
C	READ IN INITIAL INFORMATION	GUN00320
C		GUN00330
	CALL INIT	GUN00340
C		GUN00350
C	READ IN VOLTAGES FROM PREVIOUS RUN	GUN00360
C		GUN00370
	READ(8) V	GUN00380
C		GUN00390
C	READ IN CONDUCTOR CONFIGURATION	GUN00400
C		GUN00410
	CALL MESH	GUN00420
C		GUN00430
C	RELAX VOLTAGE MATRIX	GUN00440
C		GUN00450
	ERRMAX=RELERR*(CMAX-CMIN)	GUN00460
	CALL RELAX (1,1,ERROR,ERRMAX)	GUN00470
	IF (ERROR.LT.ERRMAX) GO TO 4	GUN00480
	KSTEP=1	GUN00490
1	KSTEP=2*KSTEP	GUN00500
	IF (MOD(M-1,KSTEP).NE.0) GO TO 2	GUN00510
	IF (MOD(N-1,KSTEP).NE.0) GO TO 2	GUN00520
	GO TO 1	GUN00530
2	KSTEP=KSTEP/2	GUN00540
		GUN00550

	CALL RELAX (ITER,KSTEP,ERROR,ERRMAX)	GUN00560
	IF (ERROR.LT.ERRMAX) GO TO 3	GUN00570
	CALL RELAX (ITER,1,ERROR,ERRMAX)	GUN00580
C		GUN00590
C	RECORD V MATRIX FOR NEXT USAGE	GUN00600
C		GUN00610
3	REWIND 8	GUN00620
	WRITE(8) V	GUN00630
4	WRITE(1,100) ERROR	GUN00640
C		GUN00650
C	PLOT CONTOURS	GUN00660
C		GUN00670
	CALL CONPLT (BW,NEQP)	GUN00680
C		GUN00690
C	DETERMINE EQUIPOTENTIAL SURFACE IN VICINITY OF Y=YEQP	GUN00700
C		GUN00710
	VO=PINT(X1,Y1+.75*(Y2-Y1))-COFF	GUN00720
	CALL EQPTL (VO,X1,X2,Y1,Y2)	GUN00730
C		GUN00740
C	WRITE OUT THEN CONVERT TO INCHES	GUN00750
C		GUN00760
	WRITE(1,101) VO	GUN00770
	DO 10 I=1,NXY	GUN00780
	WRITE(1,102) X(I),Y(I)	GUN00790
	X(I)=X(I)*ENGMET	GUN00800
	Y(I)=Y(I)*ENGMET	GUN00810
10	CONTINUE	GUN00820
C		GUN00830
C	GENERATE INPUT FILE FOR XMGUN	GUN00840
C		GUN00850
	WRITE(2,103) TITLE(3),VO,VO	GUN00860
	X(1)=X(2)	GUN00870
	Y(1)=.2125	GUN00880
	NCARDS=1+(NXY-1)/7	GUN00890
	WRITE(2,104) NCARDS,COND(2),COND(3)	GUN00900
	DO 20 I=1,NXY,7	GUN00910
	JF=MINO(8,NXY+1-I)	GUN00920
	WRITE(2,105) (Y(NXY+2-[-J]),X(NXY+2-[-J]),J=1,JF)	GUN00930
20	CONTINUE	GUN00940
	WRITE(2,106)	GUN00950
	STOP	GUN00960
100	FORMAT (////' MAXIMUM CHANGE IN MESH ON LAST ITERATION = ',D12.4)	GUN00970
101	FORMAT (////' COORDINATES IN METERS OF EQUIPOTENTIAL LINE ',	GUN00980
	* ' VO = ',D12.4//6X,'X',11X,'Y'/)	GUN00990
102	FORMAT (2D12.4)	GUN01000
103	FORMAT (A8,2X,2F10.0,' .10 6 2 2 100 60 10001001100',6X,	GUN01010
	* '6.'//'.21251000..0115.015 .0115.050 .0115.100 .0115')	GUN01020
104	FORMAT ('3',9X,I2,' 2',6X,2('1'F9.0))	GUN01030
105	FORMAT (8(2F5.4))	GUN01040
106	FORMAT ('.0 .200 .0 .017 .0149.017 .42911.017'	GUN01050
	* /'.41421.081.1041.1254.1041.0807.119 .0807.44391.081'	GUN01060
	* /3('0',8X),'1. .0 -.009875')	GUN01070
	END	GUN01080
C		INI00010
C	INI00020

C				INI00030
	SUBROUTINE INIT			INI00040
C				INI00050
C	RECTANGULAR GUN ANALYSIS PACKAGE			INI00060
C				INI00070
C	JOHN B RETTIG	1/31/79		INI00080
C				INI00090
C				INI00100
C	DATA INITIALIZATION ROUTINE			INI00110
C				INI00120
	IMPLICIT REAL*8 (A-H,O-Z)			INI00130
	REAL*8 V(41,401)			INI00140
	REAL*8 COND(9)			INI00150
	REAL*8 TITLE(4)			INI00160
	INTEGER ICOND(9)			INI00170
	INTEGER NCHAR(9),LINE(120),SPACE			INI00180
	DATA NCHAR /1H1,1H2,1H3,1H4,1H5,1H6,1H7,1H8,1H9/			INI00190
	DATA SPACE /1H /			INI00200
	COMMON /A/ V			INI00210
	COMMON /B/ XMIN,XMAX,DXO,			INI00220
*	YMIN,YMAX,DYO,			INI00230
*	M,N,NXY			INI00240
	COMMON /C/ COND,ICOND,NCOND,CMIN,CMAX,COFF			INI00250
	COMMON /E/ TITLE			INI00260
	DATA CMNO /1.D4/			INI00270
				INI00280
C	DATA DECK SETUP ON LOGICAL RECORD 3 (ALL UNITS MKS)			INI00290
C				INI00300
C	CARD	VARIABLE	FORMAT	DESCRIPTION
C				INI00310
C	1	TITLE(1-2)	2A8	IDENTIFICATION
C				INI00320
C	2	TITLE(3-4)	2A8	TITLE
C				INI00330
C	3	M,N	2I5	V MESH SIZE
C				INI00340
C	4	DXO,DYO	2D12.2	V MESH INCREMENTS (M)
C				INI00350
C	5-13	ICOND,COND	11,3X, F6.0	CONDUCTOR CODES - ICOND IS THE CHARACTER USED IN THE MESH TO REPRESENT POTENTIAL COND (9 OR LESS MAY BE SPECIFIED)
C				INI00360
C				INI00370
C				INI00380
C				INI00390
C				INI00400
C				INI00410
C				INI00420
C				INI00430
C				INI00440
C				INI00450
C	LAST		(END OF RECORD CARD)	INI00460
C				INI00470
C				INI00480
	READ(3,100) (TITLE(I),I=1,4),M,N			INI00490
	READ(3,101) DXO,DYO			INI00500
C				INI00510
C	ESTABLISH BOUNDARIES			INI00520
C				INI00530
	XMIN=0.			INI00540
	XMAX=XMIN+DXO*DFLCAT(M-1)			INI00550
	YMIN=0.			INI00560
	YMAX=YMIN+DYO*DFLCAT(N-1)			INI00570

C		INI00580
C	WRITE OUT GEOMETRICAL AND INITIAL CONDITION INFORMATION	INI00590
C		INI00600
	WRITE(1,102) (TITLE(I),I=1,4),M,N,	INI00610
	* XMIN,XMAX,DX0,	INI00620
	* YMIN,YMAX,DY0	INI00630
C		INI00640
C	READ CONDUCTOR CODING AND POTENTIALS	INI00650
C		INI00660
	DO 10 I=1,9	INI00670
	NCOND=I	INI00680
	READ(3,103,END=11) ICOND(I),COND(I)	INI00690
10	CONTINUE	INI00700
C		INI00710
11	NCOND=NCOND-1	INI00720
C		INI00730
C	CALCULATE MAX, MIN, AND OFFSET	INI00740
C		INI00750
	CMIN=COND(1)	INI00760
	CMAX=COND(1)	INI00770
C		INI00780
	DO 20 I=1,NCOND	INI00790
	IF (CMIN.GT.COND(I)) CMIN=COND(I)	INI00800
	IF (CMAX.LT.COND(I)) CMAX=COND(I)	INI00810
20	CONTINUE	INI00820
	COFF=CMINO-CMIN	INI00830
	RETURN	INI00840
C		INI00850
100	FORMAT (2A8/2A8/2I5)	INI00860
101	FORMAT (3D12.4)	INI00870
102	FORMAT (7777710X,'IDENT',2A87710X,'TITLE',2A877	INI00880
	* ' MESH SIZE IS ',I3,' * ',I3,' POINTS'//	INI00890
	* ' XMIN = ',D10.4,10X,'XMAX = ',D10.4,10X,'XINC = ',D10.4,	INI00900
	* ' METERS'//	INI00910
	* ' YMIN = ',D10.4,10X,'YMAX = ',D10.4,10X,'YINC = ',D10.4,	INI00920
	* ' METERS'//)	INI00930
103	FORMAT (11,3X,F6.0)	INI00940
	END	INI00950
C		MES00010
C	MES00020
C		MES00030
	SUBROUTINE MESH	MES00040
C		MES00050
C	RECTANGULAR GUN ANALYSIS PACKAGE	MES00060
C		MES00070
C	JOHN B RETTIG 1/31/79	MES00080
C		MES00090
C	THIS ROUTINE SETS UP A BRAND NEW MESH OF CONDUCTORS IN THE	MES00100
C	POTENTIAL MATRIX V. ADVANTAGE IS TAKEN OF ANY PREVIOUS	MES00110
C	SOLUTION OF A SIMILAR TYPE BY CHANGING ONLY THOSE MESH	MES00120
C	VALUES WHERE A NEW CONDUCTOR IS LOCATED.	MES00130
C		MES00140
	IMPLICIT REAL*8 (A-H,O-Z)	MES00150
	REAL*8 V(41,401)	MES00160
	REAL*8 COND(9)	MES00170

	INTEGER ICOND(9)	MES00180
	INTEGER NCHAR(9), LINE(120), SPACE	MES00190
	DATA NCHAR /1H1,1H2,1H3,1H4,1H5,1H6,1H7,1H8,1H9/	MES00200
	DATA SPACE /1H /	MES00210
	COMMON /A/ V	MES00220
	COMMON /B/ XMIN,XMAX,DX0,	MES00230
	* YMIN,YMAX,DY0,	MES00240
	* M,N,NXY	MES00250
	COMMON /C/ COND,ICOND,NCOND,CMIN,CMAX,COFF	MES00260
C		MES00270
C	DATA DECK SETUP ON LOGICAL RECORD 4 (CONDUCTOR GEOMETRY)	MES00280
C		MES00290
C	CARD VARIABLE FORMAT DESCRIPTION	MES00300
C		MES00310
C	1-N M*A1 CONDUCTOR MESH CODES	MES00320
C		MES00330
C	LAST (END OF RECORD CARD)	MES00340
C		MES00350
C		MES00360
C	READ IN CONDUCTOR INFORMATION	MES00370
C		MES00380
	DO 20 J=1,N	MES00390
	READ(4,100) (LINE(I),I=1,M)	MES00400
	DO 10 I=1,M	MES00410
	V(I,J) = DMAX1(DABS(V(I,J)),CMIN0)	MES00420
	IF (LINE(I).EQ.SPACE) GO TO 10	MES00430
	DO 11 K=1,9	MES00440
	K0=K	MES00450
	IF (LINE(I).EQ.NCHAR(K0)) GO TO 12	MES00460
11	CONTINUE	MES00470
	GO TO 30	MES00480
12	DO 13 K=1,NCOND	MES00490
	K1=K	MES00500
	IF(K0.EQ.ICOND(K1)) GO TO 14	MES00510
13	CONTINUE	MES00520
	GO TO 30	MES00530
14	V(I,J) = -(COND(K1)+COFF)	MES00540
10	CONTINUE	MES00550
20	CONTINUE	MES00560
	RETURN	MES00570
30	WRITE(1,101) J,I,(LINE(I),I=1,M)	MES00580
	STOP	MES00590
C		MES00600
100	FORMAT (120A1)	MES00610
101	FORMAT (/////' INPUT MESH ERROR',10X,' LINE ',15,	MES00620
	* 10X,' CHARACTER ',15//1X,120A1)	MES00630
	END	MES00640
C		REL00010
C	REL00020
C		REL00030
	SUBROUTINE RELAX (ITER,KSTEPS,ERROR,ERRMAX)	REL00040
C		REL00050
C	RECTANGULAR GUN ANALYSIS PACKAGE	REL00060
C		REL00070
C	JOHN B RETTIG 1/31/79	REL00080

C		REL00090
C		REL00100
C	THIS ROUTINE IMPLEMENTS THE 4-NODE DISCRETIZED LAPLACIAN	REL00110
C	OPERATOR TO SOLVE LAPLACE'S EQUATION WITHIN A SPECIFIED	REL00120
C	M*N MESH. A SUCCESSIVE OVERRELAXATION TECHNIQUE IS	REL00130
C	EMPLOYED TO PROVIDE FAST CONVERGENCE, ALONG WITH A SCHEME	REL00140
C	THAT STARTS WITH A COARSE MESH AND SUCCESSIVELY WORKS TO	REL00150
C	THE FINE MESH (I.E. EVERY SINGLE MESH POINT). THE LARGEST	REL00160
C	OF MESH GRADES EMPLOYED IS SPECIFIED BY KSTEP, WITH THE	REL00170
C	RESTRICTION THAT KSTEP BE AN INTEGRAL DIVISOR OF BOTH (M-1)	REL00180
C	AND (N-1). AFTER EACH COARSE RELAXATION IS COMPLETE, THE	REL00190
C	NEXT FINER MESH IS INTERPOLATED LINEARLY. THIS INTERPOLATION	REL00200
C	IS PERFORMED USING A FOUR NEAREST NEIGHBOR CALCULATION FIRST	REL00210
C	FOR THOSE POINTS FALLING AT DISTANCE SQRT(2) FROM THE COARSE	REL00220
C	MESH, AND THEN FOR THOSE POINTS FALLING AT DISTANCE (.5)	REL00230
C	FROM THE COARSE MESH.	REL00240
C	THE LAST FEW STEPS FOR THE FINEST GRADE MESH (KSTEP=1)	REL00250
C	RELAXATION ARE GAUSS-SEIDEL (W=.25) IN ORDER TO SMOOTH OUT	REL00260
C	THE ROUGH EDGES LEFT OVER FROM THE OVERRELAXATION.	REL00270
C		REL00280
C	IF KSTEP0=1, ONLY KSTEP=1 IS USED, AND THE PROGRAM WILL	REL00290
C	REPEAT UNTIL ERRORERRMAX. OTHERWISE, MORE COARSE MESHES ARE	REL00300
C	USED TO START, WORKING TO THE FINER MESH AND REPEATING THIS	REL00310
C	FINE MESH UNTIL ERRORERRMAX. USE CAUTION WHEN CHOOSING ERRMAX	REL00320
C	AS A 41*401 MESH TAKES ABOUT 4-5 MINUTES ON AN IBM 370/148	REL00330
C	WITH ERRMAX SET TO .01 PERCENT OF THE MAXIMUM LESS MINIMUM	REL00340
C	MESH POTENTIALS.	REL00350
C		REL00360
C	SEE CARNAHAN, LUTHER, AND WILKES, APPLIED NUMERICAL	REL00370
C	METHODS, WILEY, 1969, OR FORSYTHE AND WASOW, FINITE DIFFER-	REL00380
C	ENCE METHODS FOR PDE, WILEY, 1960.	REL00390
C		REL00400
C	IF THE MESH IS NOT ENCLOSED BY CONDUCTORS, PERIODICITY OF	REL00410
C	THE SOLUTION IS ASSUMED AND THE BOUNDARIES ARE FOLDED OVER	REL00420
C	(I.E. MIRROR IMAGE SYMMETRY IS ASSUMED). IF THIS CANNOT	REL00430
C	BE TOLERATED, BE SURE TO SPECIFY CONDUCTORS ALL THE WAY	REL00440
C	AROUND THE MESH.	REL00450
C		REL00460
C	IMPLICIT REAL*8 (A-H,C-Z)	REL00470
C	REAL*8 V(41,401)	REL00480
C	COMMON /A/ V	REL00490
C	COMMON /B/ XMIN,XMAX,DX0,	REL00500
C	* YMIN,YMAX,DY0,	REL00510
C	* M,N,NXY	REL00520
C		REL00530
C	MESH COARSENESS LOOP	REL00540
C		REL00550
C	KSTEP=2*KSTEP0	REL00560
1	KSTEP=MAX0(1,KSTEP/2)	REL00570
	KCOFF=KSTEP	REL00580
	T=3.14159/DFLOAT(MIN0(M/KSTEP,N/KSTEP))	REL00590
	W=0.5/(1.+DSIN(T))	REL00600
	IF (KSTEP0.EQ.1) W=.25	REL00610
	LMAX=ITER/KSTEP	REL00620
	IO=1	REL00630

IF=M	REL00640
JO=1	REL00650
JF=N	REL00660
C	REL00670
C	REL00680
C	REL00690
DO 30 L=1,LMAX	REL00700
ERROR=0.	REL00710
DO 20 I=10,IF,KSTEP	REL00720
IUP=I+KOFF	REL00730
IDN=I-KOFF	REL00740
IF (I.EQ.M) IUP=IDN	REL00750
IF (I.EQ.1) IDN=IUP	REL00760
DO 10 J=JO,JF,KSTEP	REL00770
VO=V(I,J)	REL00780
IF (VO.LT.0.) GO TO 10	REL00790
JUP=J+KOFF	REL00800
JDN=J-KOFF	REL00810
IF (J.EQ.N) JUP=JDN	REL00820
IF (J.EQ.1) JDN=JUP	REL00830
VOFF=W*(DABS(V(IDN,J))-VO+DABS(V(IUP,J))-VO	REL00840
* +DABS(V(I,JDN))-VO+DABS(V(I,JUP))-VO)	REL00850
V(I,J)=VO+VOFF	REL00860
ERROR=DMAX1(ERROR,DABS(VOFF))	REL00870
10 CONTINUE	REL00880
20 CONTINUE	REL00890
WRITE(6,200) L,KSTEP,W,ERROR	REL00900
C	REL00910
C	REL00920
C	REL00930
C	REL00940
IF (KSTEP.EQ.1.AND.ERROR.LT.ERRMAX.AND.W.EQ..25) RETURN	REL00950
C	REL00960
C	REL00970
C	REL00980
IF (ERROR.LT.10.*ERRMAX.AND.KSTEP.EQ.1) W=.25	REL00990
C	REL01000
30 CONTINUE	REL01010
C	REL01020
C	REL01030
C	REL01040
C	REL01050
IF (KSTEP.EQ.1) RETURN	REL01060
IF (KSTEP.EQ.1) GO TO 1	REL01070
C	REL01080
C	REL01090
C	REL01100
KCOFF=KSTEP/2	REL01110
IO=1+KCOFF	REL01120
IF=M-KCOFF	REL01130
JO=1+KCOFF	REL01140
JF=N-KCOFF	REL01150
C	REL01160
C	REL01170
C	REL01180

DC 50	J=J0,JF,KSTEP	REL01190
	JUP=J+KOFF	REL01200
	JDN=J-KOFF	REL01210
DC 40	I=I0,IF,KSTEP	REL01220
	IF (V(I,J).LT.0.) GO TO 40	REL01230
	IUP=I+KOFF	REL01240
	IDN=I-KOFF	REL01250
	V(I,J)=.25*(DABS(V(IDN,JDN))+DABS(V(IUP,JDN))	REL01260
	* +DABS(V(IDN,JUP))+DABS(V(IUP,JUP)))	REL01270
40	CONTINUE	REL01280
50	CONTINUE	REL01290
	I0=I+KOFF	REL01300
	IF=M-KOFF	REL01310
	J0=1	REL01320
	JF=N	REL01330
C		REL01340
C		REL01350
C		REL01360
	DC 70 J=J0,JF,KSTEP	REL01370
	JUP=J+KOFF	REL01380
	JDN=J-KOFF	REL01390
	IF (J.EQ.1) JDN=JUP	REL01400
	IF (J.EQ.N) JUP=JDN	REL01410
	DC 60 I=I0,IF,KSTEP	REL01420
	IF(V(I,J).LT.0.) GO TO 60	REL01430
	IUP=I+KOFF	REL01440
	IDN=I-KOFF	REL01450
	V(I,J)=.25*(DABS(V(IDN,J))+DABS(V(IUP,J))	REL01460
	* +DABS(V(I,JDN))+DABS(V(I,JUP)))	REL01470
60	CONTINUE	REL01480
70	CONTINUE	REL01490
	I0=1	REL01500
	IF=M	REL01510
	J0=1+KOFF	REL01520
	JF=N-KOFF	REL01530
	DC 90 J=J0,JF,KSTEP	REL01540
	JUP=J+KOFF	REL01550
	JDN=J-KOFF	REL01560
	DC 80 I=I0,IF,KSTEP	REL01570
	IF(V(I,J).LT.0.) GO TO 80	REL01580
	IUP=I+KOFF	REL01590
	IDN=I-KOFF	REL01600
	IF (I.EQ.M) IUP=IDN	REL01610
	IF (I.EQ.1) IDN=IUP	REL01620
	V(I,J)=.25*(DABS(V(IDN,J))+DABS(V(IUP,J))	REL01630
	* +DABS(V(I,JDN))+DABS(V(I,JUP)))	REL01640
80	CONTINUE	REL01650
90	CONTINUE	REL01660
	GC TO 1	REL01670
200	FORMAT ('***',2I10,F10.4,F10.2)	REL01680
	END	REL01690
C		CON00010
C	CON00020
C		CON00030
	SUBROUTINE CONPLT (BW,NEQP)	CON00040

RECTANGULAR GUN ANALYSIS PACKAGE

JOHN B RETTIG 1/31/79

THIS ROUTINE GENERATES A CONTOUR EQUIPOTENTIAL PLOT ON THE LINE PRINTER. CONDUCTORS, CODED AS NEGATIVE NUMBERS IN THE MESH, ARE SYMBOLIZED BY DIGITS FROM 1-9, ACCORDING TO THE SCHEME SET UP IN THE ARRAYS ICOND AND COND. OPEN SPACES ARE REPRESENTED BY LETTERS ACCORDING TO THE VALUES OF BW AND NEQP. THE PARAMETER NEQP IS THE NUMBER OF DESIRED EQUIPOTENTIALS (MAXIMUM 48), WHILE BW IS A BANDWIDTH SPECIFIER. THE WAY THE PARAMETER BW WORKS IS BEST ILLUSTRATED BY AN EXAMPLE.

ASSUME NEQP=4, BW=.10, AND $10 < V < 40$

A	$9 < V < 11$
B	$19 < V < 21$
C	$29 < V < 31$
D	$39 < V < 41$

HOWEVER, IF BW=.50 WITH ALL ELSE THE SAME

A	$7.5 < V < 12.5$
B	$17.5 < V < 22.5$
C	$27.5 < V < 32.5$
D	$37.5 < V < 42.5$

THUS, BW=0 WILL PRINT A BLANK PAGE, AND BW=1 WILL PRINT A SOLID PAGE OF CHARACTERS.

THE PARAMETER NEQP MIGHT BE ADJUSTED BY THE PROGRAM TO OBTAIN AESTHETIC EQUIPOTENTIAL SPACINGS.

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IMPLICIT REAL*8 (A-H,O-Z)
REAL*8 V(41,401)
REAL*8 COND(9)
INTEGER ICOND(9)
COMMON /A/ V
COMMON /B/ XMIN,XMAX,DXO,
*          YMIN,YMAX,DYO,
*          M,N,NXY
COMMON /C/ COND,ICOND,NCOND,CMIN,CMAX,COFF
DATA MAX /120/
INTEGER NCHAR(9),ACHAR(48),SPACE,UNIDNT,PRT(120)
DATA NCHAR /1H1,1H2,1H3,1H4,1H5,1H6,1H7,1H8,1H9/
DATA ACHAR /1HA,1HB,1HC,1HD,1HE,1HF,1HG,1HH,
*          1HJ,1HK,1HL,1HM,1HN,1HP,1HQ,1HR,
*          1HS,1HT,1HU,1HV,1HW,1HX,1HY,1HZ,
*          1HA,1HB,1HC,1HD,1HE,1HF,1HG,1HH,
*          1HJ,1HK,1HL,1HM,1HN,1HP,1HQ,1HR,
*          1HS,1HT,1HU,1HV,1HW,1HX,1HY,1HZ/
DATA SPACE /1H /, UNIDNT /1H*/

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CON00050
CON00060
CON00070
CON00080
CON00090
CON00100
CON00110
CON00120
CON00130
CON00140
CON00150
CON00160
CON00170
CON00180
CON00190
CON00200
CON00210
CON00220
CON00230
CON00240
CON00250
CON00260
CON00270
CON00280
CON00290
CON00300
CON00310
CON00320
CON00330
CON00340
CON00350
CON00360
CON00370
CON00380
CON00390
CON00400
CON00410
CON00420
CON00430
CON00440
CON00450
CON00460
CON00470
CON00480
CON00490
CON00500
CON00510
CON00520
CON00530
CON00540
CON00550
CON00560
CON00570
CON00580
CON00590

	VINC=(CMAX-CMIN)/DFLOAT(NEQP-1)	CON00600
	VLINC=DLOG10(VINC)	CON00610
	IEXP=IDINT(1.01*VLINC)	CON00620
	IFRCT=IDINT(1.01*10.** (VLINC-DFLOAT(IEXP)))	CON00630
	IF (IFRCT.EQ.7.OR.IFRCT.EQ.9) IFRCT=IFRCT+1	CON00640
	VINC=DFLOAT(IFRCT)*10.**IEXP	CON00650
	IMIN=IDINT(1.001*CMIN/VINC)	CON00660
	IMAX=1+IDINT(.999*CMAX/VINC)	CON00670
	NEQP=IMAX-IMIN+1	CON00680
	WRITE(1,100)	CON00690
	DO 10 I=1,NCOND	CON00700
	WRITE(1,101) ICOND(I),COND(I)	CON00710
10	CONTINUE	CON00720
	WRITE(1,102) BW	CON00730
	DO 20 I=1,NEQP	CON00740
	VCENT=DFLOAT(IMIN+I-1)*VINC	CON00750
	VLO=VCENT-VINC*BW/2.	CON00760
	VHI=VCENT+VINC*BW/2.	CON00770
	WRITE(1,103) ACHAR(I),VLO,VCENT,VHI	CON00780
20	CONTINUE	CON00790
	WRITE(1,104)	CON00800
	MO=MIND(MAX,M)	CON00810
	ICFF=0	CON00820
40	DO 60 J=1,N	CON00830
	DO 50 IO=1,MO	CON00840
	I=IO+ICFF	CON00850
	PRT(IO)=SPACE	CON00860
	VO=V(I,J)	CON00870
	IF (VO.LT.0.) GO TO 51	CON00880
	V1=(VO-COFF)/VINC+BW/2.	CON00890
	IV1=IDINT(V1)	CON00900
	IF(DABS(V1-DFLOAT(IV1)).GT.BW) GO TO 50	CON00910
	PRT(IO)=ACHAR(IV1-IMIN+1)	CON00920
	GO TO 50	CON00930
51	DO 52 K=1,NCOND	CON00940
	KO=K	CON00950
	IF (-VO.EQ.COND(KO)+COFF) GO TO 53	CON00960
52	CONTINUE	CON00970
	PRT(IO)=JNDINT	CON00980
	GO TO 50	CON00990
53	IV1=ICOND(KO)	CON01000
	PRT(IO)=NCHAR(IV1)	CON01010
50	CONTINUE	CON01020
	WRITE(1,105) (PRT(I),I=1,MO)	CON01030
60	CONTINUE	CON01040
	IF (MO+IOFF.GE.M) RETURN	CON01050
	ICFF=IOFF+MO	CON01060
	MO=MIND(M-IOFF,MO)	CON01070
	WRITE(1,104)	CON01080
	GO TO 40	CON01090
100	FORMAT (/////' ***** CONDUCTOR CODES *****'//	CON01100
	* 10X,' CODE VOLTS'//	CON01110
101	FORMAT (12X,I1,F12.2)	CON01120
102	FORMAT (/////' ***** POTENTIAL CODES *****'//	CON01130
	* 10X,' WINDOW = ',F6.4//	CON01140

	* CODE	LOW	MEAN	HIGH'//)	
103	FORMAT(2X,A1,4X,3F12.2)				CON01150
104	FORMAT (1H1/1HQ)				CON01160
105	FORMAT (1X,120A1)				CON01170
	END				CON01180
C					CON01190
C				EQP00010
C					EQP00020
	SUBROUTINE EQPTL (V0,X1,X2,Y1,Y2)				EQP00030
C					EQP00040
C	RECTANGULAR GUN ANALYSIS PACKAGE				EQP00050
C					EQP00060
C	JOHN B RETTIG	1/31/79			EQP00070
C					EQP00080
C					EQP00090
C					EQP00100
C	THIS PROGRAM LOCATES AND PROVIDES COORDINATES FOR THE				EQP00110
C	EQUIPOTENTIAL LINE OF VALUE V0, IN THE V MESH. A LINEAR				EQP00120
C	INTERPOLATION IS PERFORMED BETWEEN MESH POINTS. IT IS				EQP00130
C	ASSUMED THAT THE VOLTAGE MATRIX V IS STRICTLY MONOTONIC				EQP00140
C	IN THE Y DIRECTION, WITHIN A REGION ABOUT THE EQUIPOTENTIAL				EQP00150
C	LINE.				EQP00160
C					EQP00170
	IMPLICIT REAL*8 (A-H,O-Z)				EQP00180
	REAL*8 V(41,401)				EQP00190
	REAL*8 X(200),Y(200),UX(200),UY(200)				EQP00200
	COMMON /A/ V				EQP00210
	COMMON /B/ XMIN,XMAX,DX0,				EQP00220
*	YMIN,YMAX,DY0,				EQP00230
*	M,N,NXY				EQP00240
	REAL*8 COND(9)				EQP00250
	INTEGER ICOND(9)				EQP00260
	COMMON /C/ COND,ICOND,NCOND,CMIN,CMAX,COFF				EQP00270
	COMMON /D/ X,Y,UX,UY				EQP00280
	V1=V0+COFF				EQP00290
	I1=MAX0(1,1+IDINT((X1-XMIN)/DX0))				EQP00300
	I2=MIN0(M,1+IDINT((X2-XMIN)/DX0))				EQP00310
	J1=MAX0(1,1+IDINT((Y1-YMIN)/DY0))				EQP00320
	J2=MIN0(N,1+IDINT((Y2-YMIN)/DY0))				EQP00330
	NXY=0				EQP00340
	DO 10 I=I1,I2				EQP00350
	JDN=J1				EQP00360
	JUP=J2				EQP00370
	VDN=DABS(V(I,JDN))-V1				EQP00380
	VUP=DABS(V(I,JUP))-V1				EQP00390
	IF (VDN*VUP) 1,10,10				EQP00400
1	JMD=(JDN+JUP)/2				EQP00410
	VMD=DABS(V(I,JMD))-V1				EQP00420
	IF (JDN.EQ.JMD) GO TO 4				EQP00430
	IF (VDN*VMD) 2,10,3				EQP00440
2	JUP=JMD				EQP00450
	VUP=VMD				EQP00460
	GO TO 1				EQP00470
3	JDN=JMD				EQP00480
	VDN=VMD				EQP00490
	GO TO 1				EQP00500

4	NXY=NXY+1	EQP00510
	DJ=0.	EQP00520
	IF (VDN.EQ.VUP) GO TO 5	EQP00530
	DJ=VDN/(VUP-VDN)	EQP00540
5	X(NXY)=XMIN+DFLOAT(I-1)*DX0	EQP00550
	Y(NXY)=YMIN+DY0*(DFLOAT(JMD-1)-DJ)	EQP00560
10	CONTINUE	EQP00570
	RETURN	EQP00580
	END	EQP00590
C		PIN00010
C	PIN00020
C		PIN00030
	FUNCTION PINT (X,Y)	PIN00040
C		PIN00050
C	RECTANGULAR GUN ANALYSIS PACKAGE	PIN00060
C		PIN00070
C	JOHN B RETTIG 1/31/79	PIN00080
C		PIN00090
C		PIN00100
C	PINT INTERPOLATES THE V MATRIX IN BETWEEN THE MESH POINTS	PIN00110
C	USING A 4 POINT LINEAR INTERPOLATION. IF ANY BOUNDARY IS	PIN00120
C	EXCEEDED, MIRROR IMAGE SYMMETRY IS ASSUMED ABOUT THAT	PIN00130
C	BOUNDARY AND THE INTERPOLATION PERFORMED AS IF THE POINT	PIN00140
C	FELL IN THE MESH.	PIN00150
C		PIN00160
	IMPLICIT REAL*8 (A-H,O-Z)	PIN00170
	REAL*8 V(41,401)	PIN00180
	COMMON /A/ V	PIN00190
	COMMON /B/ XMIN,XMAX,DX0,	PIN00200
*	YMIN,YMAX,DY0,	PIN00210
*	M,N,NXY	PIN00220
	XINT=X	PIN00230
	YINT=Y	PIN00240
	IF (X.LT.XMIN) XINT=2.*XMIN-X	PIN00250
	IF (Y.LT.YMIN) YINT=2.*YMIN-Y	PIN00260
	IF (X.GT.XMAX) XINT=2.*XMAX-X	PIN00270
	IF (Y.GT.YMAX) YINT=2.*YMAX-Y	PIN00280
	X0=DFLOAT(M-1)*(XINT-XMIN)/(XMAX-XMIN)	PIN00290
	Y0=DFLOAT(N-1)*(YINT-YMIN)/(YMAX-YMIN)	PIN00300
	IX=1+IDINT(X0)	PIN00310
	IY=1+IDINT(Y0)	PIN00320
	FX=X0-DFLOAT(IX-1)	PIN00330
	FY=Y0-DFLOAT(IY-1)	PIN00340
	V0=DABS(V(IX,IY))	PIN00350
	V1=DABS(V(IX+1,IY))	PIN00360
	V2=DABS(V(IX,IY+1))	PIN00370
	V3=DABS(V(IX+1,IY+1))	PIN00380
	DV1=V0+(V1-V0)*FX	PIN00390
	DV2=V2+(V3-V2)*FY	PIN00400
	PINT=DV1+(DV2-DV1)*FX	PIN00410
	RETURN	PIN00420
	END	PIN00430

Appendix II

RCTGUN III

C		GUN00010
C	GUN00020
C		GUN00030
C	RECTANGULAR GUN ANALYSIS PACKAGE	GUN00040
C		GUN00050
C	JOHN B RETTIG 1/31/79	GUN00060
C		GUN00070
C	MAIN DRIVER ROUTINE, PART III- TRAJECTORY CALCULATIONS	GUN00080
C		GUN00090
	IMPLICIT REAL*8 (A-H,O-Z)	GUN00100
	REAL*8 V(41,401)	GUN00110
	REAL*8 COND(9)	GUN00120
	REAL*8 X(200),Y(200),UX(200),UY(200)	GUN00130
	INTEGER ICOND(9)	GUN00140
	COMMON /A/ V	GUN00150
	COMMON /B/ XMIN,XMAX,DXO,	GUN00160
	* YMIN,YMAX,DYO,	GUN00170
	* M,N,NXY	GUN00180
	COMMON /C/ COND,ICOND,NCOND,CMIN,CMAX,COFF	GUN00190
	COMMON /D/ X,Y,UX,UY	GUN00200
	COMMON /E/ TITLE1,TITLE2,TITLE3,TITLE4	GUN00210
	CALL INIT	GUN00220
	READ(8) V	GUN00230
	CALL TRAJ	GUN00240
	STOP	GUN00250
	END	GUN00260
C	INI00010
C		INI00020
C		INI00030
	SUBROUTINE INIT	INI00040
C		INI00050
C	RECTANGULAR GUN ANALYSIS PACKAGE	INI00060
C		INI00070
C	JOHN B RETTIG 1/31/79	INI00080
C		INI00090
C		INI00100
C	DATA INITIALIZATION ROUTINE	INI00110
C		INI00120
	IMPLICIT REAL*8 (A-H,O-Z)	INI00130
	REAL*8 V(41,401)	INI00140
	REAL*8 COND(9)	INI00150
	REAL*8 TITLE(4)	INI00160
	INTEGER ICOND(9)	INI00170
	INTEGER NCHAR(9),LINE(120),SPACE	INI00180
	DATA NCHAR /1H1,1H2,1H3,1H4,1H5,1H6,1H7,1H8,1H9/	INI00190
	DATA SPACE /1H /	INI00200
	COMMON /A/ V	INI00210
	COMMON /B/ XMIN,XMAX,DXO,	INI00220
	* YMIN,YMAX,DYO,	INI00230
	* M,N,NXY	INI00240
	COMMON /C/ COND,ICOND,NCOND,CMIN,CMAX,COFF	INI00250
	COMMON /E/ TITLE	INI00260
	DATA CMINO /1.04/	INI00270
C		INI00280
C	DATA DECK SETUP ON LOGICAL RECORD 3 (ALL UNITS MKS)	INI00290

CARD	VARIABLE	FORMAT	DESCRIPTION	
1	TITLE(1-2)	2A8	IDENTIFICATION	INI00300
2	TITLE(3-4)	2A8	TITLE	INI00310
3	M,N	2I5	V MESH SIZE	INI00320
4	DXC,DYO	2D12.2	V MESH INCREMENTS (M)	INI00330
5-13	ICOND,COND	11,3X, F6.0	CONDUCTOR CODES - ICOND IS THE CHARACTER USED IN THE MESH TO REPRESENT POTENTIAL COND (9 OR LESS MAY BE SPECIFIED)	INI00340
LAST			(END OF RECCRD CARD)	INI00350
READ(3,100) (TITLE(I),I=1,4),M,N				INI00360
READ(3,101) DXC,DYO				INI00370
ESTABLISH BOUNDARIES				INI00380
XMIN=0.				INI00390
XMAX=XMIN+DXC*DFLOAT(M-1)				INI00400
YMIN=0.				INI00410
YMAX=YMIN+DYO*DFLOAT(N-1)				INI00420
WRITE OUT GEOMETRICAL AND INITIAL CONDITION INFORMATION				INI00430
WRITE(1,102) (TITLE(I),I=1,4),M,N,				INI00440
* XMIN,XMAX,DXC,				INI00450
* YMIN,YMAX,DYO				INI00460
READ CONDUCTOR CODING AND POTENTIALS				INI00470
DO 10 I=1,9				INI00480
NCOND=I				INI00490
READ(3,103,END=11) ICOND(I),COND(I)				INI00500
10	CONTINUE			INI00510
11	NCOND=NCOND-1			INI00520
CALCULATE MAX, MIN, AND OFFSET				INI00530
CMIN=COND(1)				INI00540
CMAX=COND(1)				INI00550
DO 20 I=1,NCOND				INI00560
IF (CMIN.GT.COND(I)) CMIN=COND(I)				INI00570
IF (CMAX.LT.COND(I)) CMAX=COND(I)				INI00580
20	CONTINUE			INI00590
COFF=CMINO-CMIN				INI00600
RETURN				INI00610

C		INI00850
100	FORMAT (2A8/2A8/2I5)	INI00860
101	FORMAT (3D12.4)	INI00870
102	FORMAT (//////10X,'IDENT',2A8//10X,'TITLE',2A8//	INI00880
*	' MESH SIZE IS ',I3,' * ',I3,' POINTS'//	INI00890
*	' XMIN = ',D10.4,10X,' XMAX = ',D10.4,10X,' XINC = ',D10.4,	INI00900
*	' METERS'//	INI00910
*	' YMIN = ',D10.4,10X,' YMAX = ',D10.4,10X,' YINC = ',D10.4,	INI00920
*	' METERS'//)	INI00930
103	FORMAT (I1,3X,F6.0)	INI00940
	END	INI00950
C		TRA00010
C	TRA00020
C		TRA00030
	SUBROUTINE TRAJ	TRA00040
C		TRA00050
C	RECTANGULAR GUN ANALYSIS PACKAGE	TRA00060
C		TRA00070
C	JOHN B RETTIG 1/31/79	TRA00080
C		TRA00090
C		TRA00100
C	THIS PROGRAM FINDS THE TRAJECTORY OF A CHARGED PARTICLE IN	TRA00110
C	THE PRESENCE OF AN ELECTRIC FIELD CREATED BY CONDUCTORS OF	TRA00120
C	VARIOUS POTENTIALS. THERMAL EFFECTS, RELATIVITY, AND SPACE	TRA00130
C	CHARGE EFFECTS ARE NOT TAKEN INTO ACCOUNT. FIELD GRADIENTS	TRA00140
C	ARE TAKEN FROM THE POTENTIAL MATRIX V (ASSUMED TO HAVE ALREADY	TRA00150
C	BEEN SOLVED BY SOME MEANS). THEN, A DISCRETIZED FOURTH	TRA00160
C	ORDER DISCRETIZED RUNGE-KUTTA INTEGRATION SCHEME IS USED TO	TRA00170
C	PIECE OUT THE PATH OF THE PARTICLE THROUGH THE MATRIX.	TRA00180
C		TRA00190
C	IF DESIRED, PARTICLES MAY BE BOUNCED OFF OF BOUNDARIES ABOUT	TRA00200
C	WHICH THE FIELD IS ASSUMED TO BE MIRROR IMAGE SYMMETRICAL.	TRA00210
C		TRA00220
C		TRA00230
C		TRA00240
C	DATA DECK SETUP ON LOGICAL RECORD 5	TRA00250
C		TRA00260
C	CARD VARIABLE FORMAT DESCRIPTION	TRA00270
C		TRA00280
C	1 X1,Y1,U1,P1 3D12.4, INITIAL POSITION AND VELOCITY	TRA00290
C	F12.2 FOR PARTICLE 1 - X1 AND Y1 IN	TRA00300
C	METERS, U1 IN METERS/S, P1 IN	TRA00310
C	DEGREES FROM +X AXIS	TRA00320
C		TRA00330
C	2+ (SAME FOR PARTICLE 2, ETC)	TRA00340
C		TRA00350
C	LAST (END OF RECORD CARD)	TRA00360
C		TRA00370
C		TRA00380
	IMPLICIT REAL*8 (A-H,O-Z)	TRA00390
	REAL*8 X(200),Y(200),UX(200),UY(200)	TRA00400
	COMMON /B/ XMIN,XMAX,DX0,	TRA00410
*	YMIN,YMAX,DY0,	TRA00420
*	M,N,NXY	TRA00430
	COMMON /C/ CONE,ICOND,NCONE,CMIN,CMAX,COFF	TRA00440

```

COMMON /D/ X,Y,UX,UY
REAL*8 F(4),Z(4)
EQUIVALENCE (X1,Z(1)),(Y1,Z(2)),(UX1,Z(3)),(UY1,Z(4))
INTEGER RUNGE
DATA TMIN /0./
DATA DT /2.D-11/
DATA PI /3.1415926535D+0/

```

```

C      ELECTRON CHARGE/MASS, MKS

```

```

C      DATA ETA /1.7587945D11/
C      TMAX=TMIN+2.*(YMAX-YMIN)/DSQRT(2.*ETA*(CMAX-CMIN))

```

```

C      I=0
10     I=I+1
      READ(5,100,END=30) X1,Y1,U1,P1
      RO=(PI/180.)*P1
      UX1=U1*DCOS(RO)
      UY1=U1*DSIN(RO)
      X(1)=X1
      Y(1)=Y1
      UX(1)=UX1
      UY(1)=UY1
      NXY=1
      T=TMIN

```

```

C      COMPUTE STEP

```

```

11     K=RUNGE (4,Z,F,T,DT)

```

```

C      K=1 FLAG THAT DERIVATIVES ARE NEEDED

```

```

C      IF (K.NE.1) GO TO 12

```

```

C      COMPUTE GRADIENTS IN POTENTIAL USING CENTRAL DIFFERENCES

```

```

C      VXH=PINT(X1+.5*DXC,Y1)
C      VXL=PINT(X1-.5*DXC,Y1)
C      VYH=PINT(X1,Y1+.5*DYC)
C      VYL=PINT(X1,Y1-.5*DYC)

```

```

C      GRADVX=(VXH-VXL)/DXC
C      GRADVY=(VYH-VYL)/DYC

```

```

C      COMPUTE DERIVATIVES AND CONTINUE RUNGE INTEGRATION

```

```

C      - F(1)=DX/DT=UX
C      - F(2)=DY/DT=UY
C      - F(3)=DUX/DT=ETA*GRADVX
C      - F(4)=DUY/DT=ETA*GRADVY

```

```

C      F(1)=UX1
C      F(2)=UY1
C      F(3)=ETA*GRADVX
C      F(4)=ETA*GRADVY

```

```

TRA0045C
TRA00460
TRA00470
TRA00480
TRA00490
TRA00500
TRA00510
TRA00520
TRA00530
TRA00540
TRA00550
TRA00560
TRA00570
TRA00580
TRA00590
TRA00600
TRA00610
TRA00620
TRA00630
TRA00640
TRA00650
TRA00660
TRA00670
TRA00680
TRA00690
TRA00700
TRA00710
TRA00720
TRA00730
TRA00740
TRA00750
TRA00760
TRA00770
TRA00780
TRA00790
TRA00800
TRA00810
TRA00820
TRA00830
TRA00840
TRA00850
TRA00860
TRA00870
TRA00880
TRA00890
TRA00900
TRA00910
TRA00920
TRA00930
TRA00940
TRA00950
TRA00960
TRA00970
TRA00980
TRA00990

```

C		TRA01000
C	GO TO 11	TRA01010
C		TRA01020
12	NXY=NXY+1	TRA01030
C		TRA01040
C	BOUNCE OFF DESIRED BOUNDARIES	TRA01050
C		TRA01060
	IF (X1.GT.XMIN) GO TO 13	TRA01070
	X1 =2.*XMIN-X1	TRA01080
	UX1 =-UX1	TRA01090
13	CCONTINUE	TRA01100
C	IF (Y1.GT.YMIN) GO TO 14	TRA01110
C	Y1=2.*YMIN-Y1	TRA01120
C	UY1=-UY1	TRA01130
C14	CCONTINUE	TRA01140
C	IF (X1 .LT.XMAX) GO TO 15	TRA01150
C	X1 =2.*XMAX-X1	TRA01160
C	UX1 =-UX1	TRA01170
C15	CCONTINUE	TRA01180
C	IF (Y1.LT.YMAX) GO TO 16	TRA01190
C	Y1=2.*YMAX-Y1	TRA01200
C	UY1=-UY1	TRA01210
C16	CCONTINUE	TRA01220
C		TRA01230
C	RECORD POSITIONS	TRA01240
C		TRA01250
	X(NXY)=X1	TRA01260
	Y(NXY)=Y1	TRA01270
	UX(NXY)=UX1	TRA01280
	UY(NXY)=UY1	TRA01290
C		TRA01300
C	CHECK LIMITS	TRA01310
C		TRA01320
	IF (X1.LT.XMIN.OR.X1.GT.XMAX.OR.Y1.LT.YMIN.OR.Y1.GT.YMAX	TRA01330
*	.OR.T.GT.TMAX.OR.NXY.EQ.200) GO TO 20	TRA01340
	GO TO 11	TRA01350
C		TRA01360
C	PRINT AND PLOT INFORMATION	TRA01370
C		TRA01380
20	WRITE(1,101) I	TRA01390
	DO 21 K=1,NXY	TRA01400
	T=TMIN+DFLOAT(K-1)*DT	TRA01410
	U=DSQRT(UX(K)*UX(K)+UY(K)*UY(K))	TRA01420
	ANG=(180./PI)*DATAN2(UY(K),UX(K))	TRA01430
	WRITE(1,102) T,X(K),Y(K),U,ANG	TRA01440
21	CCONTINUE	TRA01450
	CALL TJPLOT	TRA01460
	GO TO 10	TRA01470
30	CALL POFF	TRA01480
	RETURN	TRA01490
C		TRA01500
100	FORMAT (3D12.4,F12.2)	TRA01510
101	FORMAT (//////10X,' ***** PARTICLE ',I2,' *****'//	TRA01520
*	6X,'T(S)',8X,'X(M)',8X,'Y(M)',8X,'U(M/S)',6X,'ANGLE')	TRA01530
102	FORMAT (1X,4D12.3,F10.2)	TRA01540

C	END	TRA01550
C	RUN00010
C		RUN00020
C	FUNCTION RUNGE (N,Y,F,X,H)	RUN00030
C		RUN00040
C	RECTANGULAR CUN ANALYSIS PACKAGE	RUN00050
C		RUN00060
C	JOHN B RETTIG 1/31/79	RUN00070
C		RUN00080
C		RUN00090
C	FOURTH ORDER RUNGE-KUTTA INTEGRATION	RUN00100
C		RUN00110
C		RUN00120
C	COPIED FROM CARNAHAN, LUTHER, & WILKES, 'APPLIED NUMERICAL	RUN00130
C	METHODS', NEW YORK, WILEY, 1969, PP 374-5.	RUN00140
C		RUN00150
C	IMPLICIT REAL*8 (A-H,O-Z)	RUN00160
C	INTEGER RUNGE	RUN00170
C	REAL*8 PHI(4),SAVEY(4),Y(N),F(N)	RUN00180
C	DATA M/0/	RUN00190
C		RUN00200
C	M=M+1	RUN00210
C	GO TO (1,2,3,4,5),M	RUN00220
C		RUN00230
CPASS 1....	RUN00240
1	RUNGE=1	RUN00250
	RETURN	RUN00260
C		RUN00270
CPASS 2....	RUN00280
2	DO 22 J=1,N	RUN00290
	SAVEY(J)=Y(J)	RUN00300
	PHI(J)=F(J)	RUN00310
22	Y(J)=SAVEY(J)+0.5*H*F(J)	RUN00320
	X=X+0.5*H	RUN00330
	RUNGE=1	RUN00340
	RETURN	RUN00350
C		RUN00360
CPASS 3....	RUN00370
3	DO 33 J=1,N	RUN00380
	PHI(J)=PHI(J)+2.0*F(J)	RUN00390
33	Y(J)=SAVEY(J)+0.5*H*F(J)	RUN00400
	RUNGE=1	RUN00410
	RETURN	RUN00420
C		RUN00430
CPASS 4....	RUN00440
4	DO 44 J=1,N	RUN00450
	PHI(J)=PHI(J)+2.0*F(J)	RUN00460
44	Y(J)=SAVEY(J)+F*F(J)	RUN00470
	X=X+0.5*H	RUN00480
	RUNGE=1	RUN00490
	RETURN	RUN00500
C		RUN00510
CPASS 5....	RUN00520
5	DO 55 J=1,N	RUN00530
55	Y(J)=SAVEY(J)+(PHI(J)+F(J))*H/6.0	RUN00540

M=0	RUN00550
RUNGE=0	RUN00560
RETURN	RUN00570
C	RUN00580
END	RUN00590
C	PIN00010
C	PIN00020
C	PIN00030
FUNCTION PINT (X,Y)	PIN00040
C	PIN00050
RECTANGULAR GUN ANALYSIS PACKAGE	PIN00060
C	PIN00070
JOHN B RETTIG 1/31/79	PIN00080
C	PIN00090
C	PIN00100
PINT INTERPOLATES THE V MATRIX IN BETWEEN THE MESH POINTS	PIN00110
USING A 4 POINT LINEAR INTERPOLATION. IF ANY BOUNDARY IS	PIN00120
EXCEEDED, MIRROR IMAGE SYMMETRY IS ASSUMED ABOUT THAT	PIN00130
BOUNDARY AND THE INTERPOLATION PERFORMED AS IF THE POINT	PIN00140
FELL IN THE MESH.	PIN00150
C	PIN00160
IMPLICIT REAL*8 (A-H,O-Z)	PIN00170
REAL*8 V(41,401)	PIN00180
COMMON /A/ V	PIN00190
COMMON /B/ XMIN,XMAX,DX0,	PIN00200
* YMIN,YMAX,DY0,	PIN00210
* M,N,NXY	PIN00220
XINT=X	PIN00230
YINT=Y	PIN00240
IF (X.LT.XMIN) XINT=2.*XMIN-X	PIN00250
IF (Y.LT.YMIN) YINT=2.*YMIN-Y	PIN00260
IF (X.GT.XMAX) XINT=2.*XMAX-X	PIN00270
IF (Y.GT.YMAX) YINT=2.*YMAX-Y	PIN00280
X0=DFLOAT(M-1)*(XINT-XMIN)/(XMAX-XMIN)	PIN00290
Y0=DFLOAT(N-1)*(YINT-YMIN)/(YMAX-YMIN)	PIN00300
IX=1+IDINT(X0)	PIN00310
IY=1+IDINT(Y0)	PIN00320
FX=X0-DFLOAT(IX-1)	PIN00330
FY=Y0-DFLOAT(IY-1)	PIN00340
V0=DABS(V(IX,IY))	PIN00350
V1=DABS(V(IX+1,IY))	PIN00360
V2=DABS(V(IX,IY+1))	PIN00370
V3=DABS(V(IX+1,IY+1))	PIN00380
DV1=V0+(V1-V0)*FX	PIN00390
DV2=V2+(V3-V2)*FX	PIN00400
PINT=DV1+(DV2-DV1)*FY	PIN00410
RETURN	PIN00420
END	PIN00430
C	TJP00010
C	TJP00020
C	TJP00030
SUBROUTINE TJPLUT	TJP00040
C	TJP00050
RECTANGULAR GUN ANALYSIS PACKAGE	TJP00060
C	TJP00070

C	JOHN B RETTIG	1/31/79	TJP00080
C			TJP00090
C			TJP00100
C	TRAJECTORY PLOT SETUP FOR THE ZETA PLOTTER		TJP00110
C			TJP00120
	REAL*8 V(41,401)		TJP00130
	REAL*8 X(200),Y(200),UX(200),UY(200)		TJP00140
	REAL*8 XMIN,XMAX,DX0,YMIN,YMAX,DY0,TMIN,TMAX,DT		TJP00150
	COMPLEX*16 IDENT,TITLE		TJP00160
	COMMON /A/ V		TJP00170
	COMMON /B/ XMIN,XMAX,DX0,		TJP00180
	* YMIN,YMAX,DY0,		TJP00190
	* M,N,NXY		TJP00200
	COMMON /D/ X,Y,UX,UY		TJP00210
	COMMON /E/ IDENT,TITLE		TJP00220
	DATA WIDTH /4./		TJP00230
	DATA IFLAG /0/		TJP00240
C			TJP00250
C	FIRST TIME THROUGH?		TJP00260
C			TJP00270
	IF (IFLAG.NE.0) GO TO 50		TJP00280
	IFLAG=1		TJP00290
	CALL PLOTF (10,2)		TJP00300
	CALL FACTOR (2.)		TJP00310
C			TJP00320
C	DEFINE SCALES		TJP00330
C			TJP00340
	XL=WIDTH		TJP00350
	YL=WIDTH*SNGL((YMAX-YMIN)/(XMAX-XMIN))		TJP00360
	DX=SNGL(XMAX-XMIN)/XL		TJP00370
	DY=SNGL(YMAX-YMIN)/YL		TJP00380
	X0=SNGL(XMIN)		TJP00390
	Y0=SNGL(YMIN)		TJP00400
C			TJP00410
C	TITLE		TJP00420
C			TJP00430
	CALL SYMBOL (YL/3.,XL+1.,.15,IDENT,0.,16)		TJP00440
	CALL SYMBOL (YL/3.,XL+.50,.15,TITLE,0.,16)		TJP00450
C			TJP00460
C	SCALE ALL FUTURE PLOTTING TO GUN DIMENSIONS		TJP00470
C			TJP00480
	CALL OFFSET (Y0,DY,X0,DX)		TJP00490
C			TJP00500
C	DRAW CONDUCTORS		TJP00510
C			TJP00520
	DO 20 I=1,M		TJP00530
	X0=SNGL(DX0)*FLOAT(I-1)		TJP00540
	JTEST=0		TJP00550
	DO 10 J=1,N		TJP00560
	IF (V(I,J).LT.0..AND.JTEST.EQ.0) GO TO 11		TJP00570
	IF (V(I,J).GT.0..AND.JTEST.EQ.1) GO TO 12		TJP00580
	IF (J.EQ.N..AND.JTEST.EQ.1) GO TO 12		TJP00590
	GO TO 10		TJP00600
11	JTEST=1		TJP00610
	JSTART=J		TJP00620

	GC TC 10	TJP00630
12	JTEST=0	TJP00640
	JSTOP=J-1	TJP00650
	IF (J.EQ.N) JSTOP=J	TJP00660
	IF(JSTART.EQ.JSTOP) GO TO 10	TJP00670
	YO=SNGL(DYO)*FLOAT(JSTART-1)	TJP00680
	CALL PLOTX (YO,XO,13)	TJP00690
	YO=SNGL(DYO)*FLOAT(JSTOP-1)	TJP00700
	CALL PLOTX (YO,XO,12)	TJP00710
10	CONTINUE	TJP00720
20	CONTINUE	TJP00730
C		TJP00740
	DC 40 J=1,N	TJP00750
	YO=SNGL(DYO)*FLOAT(J-1)	TJP00760
	ITEST=0	TJP00770
	DC 30 I=1,M	TJP00780
	IF (V(I,J).LT.C..AND.ITEST.EQ.0) GO TO 31	TJP00790
	IF (V(I,J).GT.C..AND.ITEST.EQ.1) GO TO 32	TJP00800
	IF (I.EQ.M.AND.ITEST.EQ.1) GO TO 32	TJP00810
	GO TO 30	TJP00820
31	ITEST=1	TJP00830
	ISTART=I	TJP00840
	GO TO 30	TJP00850
32	ITEST=0	TJP00860
	ISTOP=I-1	TJP00870
	IF (I.EQ.M) ISTOP=I	TJP00880
	IF(ISTART.EQ.ISTOP) GO TO 30	TJP00890
	XO=SNGL(DXO)*FLOAT(ISTART-1)	TJP00900
	CALL PLOTX (YO,XO,13)	TJP00910
	XO=SNGL(DXO)*FLOAT(ISTOP-1)	TJP00920
	CALL PLOTX (YO,XO,12)	TJP00930
30	CONTINUE	TJP00940
40	CONTINUE	TJP00950
50	CALL LINE (Y,X,NXY,2,0,12)	TJP00960
	RETURN	TJP00970
C		TJP00980
	END	TJP00990

Appendix III

BEAMSPREAD

```

      gular  "*"
1: prt  "*" Beams
   read  "*" : spc 2
2: dim Q$(11),
   R(3),A$(13,20)
3: 1.758e11+N;
   8.856e-12+E;
   flt 3
4: cfs 13: enp
   "Number of disc
   rete intervals?"
   ",M: if flt 13;
   jmp 0
5: dim J(2,M);
   Y(0:M)
6: cfs 13: enp
   "Spacing of
   intervals (M)?"
   ",S: if flt 13;
   jmp 0
7: dsp "Enter
   initial current
   densities";
   wait 2000
8: for I=1 to M
9:  enp J(1,I);
   next I
10: ""+Q$;ent
   "Want profile
   plot(Y/N)?":Q$
11: cfs 0: if
   cdp(Q$)="Y";
   sfs 0: 0+R(1);
   9+R(2);12+R(3);
   trk 0: ldf 10
12: if not flt 0;
   ato "Drift"
13: plt 0,0,1
14: for I=1 to M
15: plt S(I-1),
   J(1,I),2

```

```

19: flt 3
20: "Drift":
21: cfs 13: enp
   "Acceleration
   potential (kV)?"
   ",V: if flt 13;
   jmp 0
22: cfs 13: enp
   "Drift space
   (M)?",D: if flt 1
   3: jmp 0
23: 0+K+Y(0);
   (1000V)/(1-3/
   2)DD/4Er(2N)+C
24: for I=1 to
   M: K+SJ(1,I)+K
25: IS+CK+Y(I);
   J(1,I)(S/(Y(I)-
   Y(I-1)))+J(2,I)
26: spc :prt "Y
   = ",Y(I),"J =
   ",J(2,I)
27: next I: spc
28: prt "K = ",
   K," A/M": spc 3
29: if not flt 0;
   ato "Drift"
30: plt 0,0,1
31: for I=1 to M
32: plt Y(I-1),
   J(2,I),2
33: plt Y(I),
   J(2,I),2
34: next I
35: plt Y(M),0,
   2: pen
36: ato "Drift"
37: end

```


Appendix IV

CONVOLVE

```

Beam      * , "
Convolution *
" : spc 2
1: dim M[2];dim
G[-16:16];dim
Y[65];dim N[3];
rad
2: enp "Diode
spacing?";S;
"Diode width?";
M
3: enp "No. beam
points?";Q;
"Increment betw
een points?";D
4: enp "Start
beam drive?";
N[1];"End beam
drive?";N[3];
"Increment?";
N[2]
5: enp "Pos.
sens.?" ;M[1];
"Neg. sens.?" ;
M[2];"Data sour
ce?";r2
6: if r2#0;enp
"File?";r9;jmp
3
7: enp "Beam
type?";r16
8: if r16;enp
"Truncation?";
r17
9: enp "Highest
harmonic?";C;
"Plot?";r8;"Sat
uration drop?";
r12
10: if r8=1;sf
1
...
C=0;N=

```

```

-1;
14: if r8=2;sf
3
15: dim F[-Q:Q]
16: if N[2]=0;
jmp 3
17: (N[3]-N[1])/
N[2]+r5
18: dim P[2,0:r5
+1]
19: M+S+L
20: "Beam":c11
"Generate"(Q)
21: c11 "Zero"
22: enp "DC Tran
sfer?";r1
23: if r1;c11
"DC"
24: fmt 2,f6.2,
2x,e8.2
25: spc iflt 4;
prt "Beam profi
le":spc
26: for I=-Q to
Q;wrt 16.2;ID;
F[I];next I
27: N[1]+r3;0+r1
28: "Response":s
pc
29: c11 "Convolve"
30: c11 "Fourier"
"(C)
31: c11 "Efficie
ncy"
32: if N[2]=0;
eto "Quit"
33: (r3-N[1])/
N[2]+r4
34: r3+2+P[1,r4]
35:

```

```

"Response"
37: max(F[*])→r1
38: if F[1]≥.5r
13: jmp 2
39: 1-1>0→I: jmp
-1
40: min(S+ID, S-
ID+W)→r3
41: cll "Convolve"
42: cll "Fourier"
43: R[1]↑2+P[2,
r5+1]
44: dsp "Transfer
plot"
45: sto
46: scl -20,10,-
20,10
47: axs 0,0,2,2;
sfs 14
48: for I=0 to
r5:10log(P[1,
1]/r3↑2)+X:10lo
g(P[2,I]/P[2,
r5+1])→Y
49: prt "Pin",X;
"Pout",Y:spc
50: if X<-20:-
20+X
51: if Y<-20:-
20+Y
52: plt X,Y
53: next I
54: pen:plt -20,
-20:pen
55: "Quit":prt
*****
**":spc 3:end
56: "Generate":i

```

```

58: if r16: jmp 3
59: for I=-p1
to p1:1→F[I]
60: next I: jmp 6
61: for I=-p1
to p1: if (exp(-
6.9I↑2/Q↑2)+F[I
1])>r17: r17→F[I]
62: next I: jmp 4
63: "Data": for
I=-p1 to p1:
ent F[I]
64: next I
65: trk 1: rcf
r9,F[*]: trk 0
66: ret
67: "Tape": trk
1: ldf r9,F[*]:
trk 0
68: ret
69: "Fourier": m/
32→p2
70: esb "Four"
71: if p1=0: sto
"Finish"
72: prt "Fourier
Current Harmon
ics (dB)": spc
73: fwt 0,1,0,
48.2
74: if (abs(R[0]
/R[1])+r7)>1e-
10: prt 16,"R[",
0,"] = ",20log(
r7)
75: for I=1 to N
76: if (abs(R[I]
/R[1])+r7)>1e-
10: prt 16,"R[",

```

```

10: wrt 16, "B[";
I, "I" = ",201os(
r7)
78: apc inext I
79: "Finish":ret

80: "Four":rad;
cfe 2;1+J;0+I;
2π+p3
81: if (I+1+I)>6
5:eto +8
82: -π+(I-1)p2+X
;Y[I]+Y;if I=1
or I=65;1+M;
eto +3
83: if M=4;2+M;
eto +2
84: 4+M
85: cos(2πX/p3+E
)+p4+F;sin(E)+p
5+G
86: MYF+A[J]+A[J
];MYG+B[J]+B[J]
87: if (J+1+J)<=
N;p4F-p5G+T;
p5F+p4G+G;T+F;
eto -1
88: 1+J;eto -7
89: Y[I]+4Y[2]+
Y[65]+p4;3+1
90: p4+2Y[I]+
4Y[I+1]+p4;jmp
(I+2+I)>=65
91: p4p2/3p3+R[0
];1+J
92: 2A[J]p2/3p3+
A[J];2B[J]p2/
3p3+B[J];jmp
(J+1+J)>N
93: ret

```

```

)+r10
96: next I
97: if r10=0;
0+r11;jmp 2
98: 32A[I]r12/
r10+r11
99: fxd 2;prt
"Displ = ",r3
100: fxd 4;prt
"Efflc = ",r11
101: apc ;ret
102: "Convolve";
for I=-16 to 16
103: 0+G[I]
104: r3sin(Iπ/
32)+P
105: for J=-Q
to Q
106: if abs(F+
JD)>L;0+H;eto
"Sum"
107: if abs(P+
JD)<S;0+H;eto
"Sum"
108: if P+JD<=-
S;-M[2]+H;eto
"Sum"
109: if P+JD>=S;
M[1]+H
110: "Sun":F[J]H
D+G[I]+G[I]
111: next J
112: next I
113: max(G[*])+Z
114: for I=-16
to 16;G[I]+Y[I+
17]
115: next I
116: for I=15
to -16 by -1;

```



```

9π/4,-1.2,1.2
120: if fl=1;
  jmp 3
121: oxe 0,0,π/
  4,.2
122: sfa 1
123: for K=1 to
  65
124: plt (K-1)π/
  32,Y[K]/Z
125: next K
126: pen
127: "Done":ret
128: "DC":end
  "No. of transfe
  r points",p1
129: 1.5(W+S)/
  p1+p2
130: for I=1 to
  p1;p2+p
131: 0+p3
132: for J=-Q
  to Q
133: if abs(P+
  JD)<S;0+H;sto
  "Add"
134: if abs(P+
  JD)>L;0+H;sto
  "Add"
135: if P+JD<=-
  S;-M[2]+H;sto
  "Add"
136: if P+JD>=S;
  M[1]+H
137: "Add":F[J]H
  D+p3+p3
138: next J
139: prt "Drive"
  ,p2,"Current",
  p2:--

```

```

to W
144: if abs(JD)<
  S;0+H;sto "Tota
  l"
145: if abs(JD)>
  L;0+H;sto "Tota
  l"
146: if JD<=-S;
  M[2]+H;sto "Tot
  al"
147: if JD>=S;
  M[1]+H
148: "Total":F[J
  ]HD+r6+r6
149: next J

```

Appendix IV
KEY PERSONNEL

DOUGLAS B. CLARK, Member of the Technical Staff, Tube Division, Devices Group. Born December 31, 1946, Oakland, California. Nine years experience. B.S., Electrical Engineering, University of California at Berkeley, 1969. Graduate studies in Electrical Engineering at Loyola University of Los Angeles.

Mr. Clark is currently a Project Engineer with the Electron Bombarded Semiconductors Group. He is responsible for design and development of state-of-the-art EBS devices.

From February 1974 to May 1977, Mr. Clark was with the Solid State West Division of Varian Associates in Palo Alto, California. He was Project Engineer on a variety of development and production projects involving Gun diode amplifiers, YIG-tuned Gunn Oscillators, and bipolar transistor amplifiers.

From June 1969 to February 1974, Mr. Clark was with the Hughes Aircraft Company, Electron Dynamics Division, where he was a Member of the Technical Staff. His responsibilities included that of Project Engineer on state-of-the-art, dual mode, multi-octave traveling-wave tubes. He also was responsible for production of high pulse power space tubes.

JOHN B. RETTIG, Member of the Technical Staff, Tube Division. Born
January 8, 1954, Toledo, Ohio. B.S.E.E., 1977, M.S.E.E.,
1978, Purdue University.

Mr. Rettig is presently working on the development of an EBS space amplifier for NASA Goddard Research Center that must meet stringent linearity and efficiency specifications.

Formerly he was a research assistant at Purdue University, engaged in High Gradient Magnetic Separation studies. This involved experimental quantization of 3-dimensional buildups of small paramagnetic particles on saturated ferromagnetic wires.

Mr. Rettig is a member of Tau Beta Pi and IEEE.